

Test-Beam Results of the AMS 180 HVCMOS prototypes

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On behalf of: CERN, Genova INFN, Karlsruhe Institute of Technology,
Liverpool University, University of Bern and University of Geneva

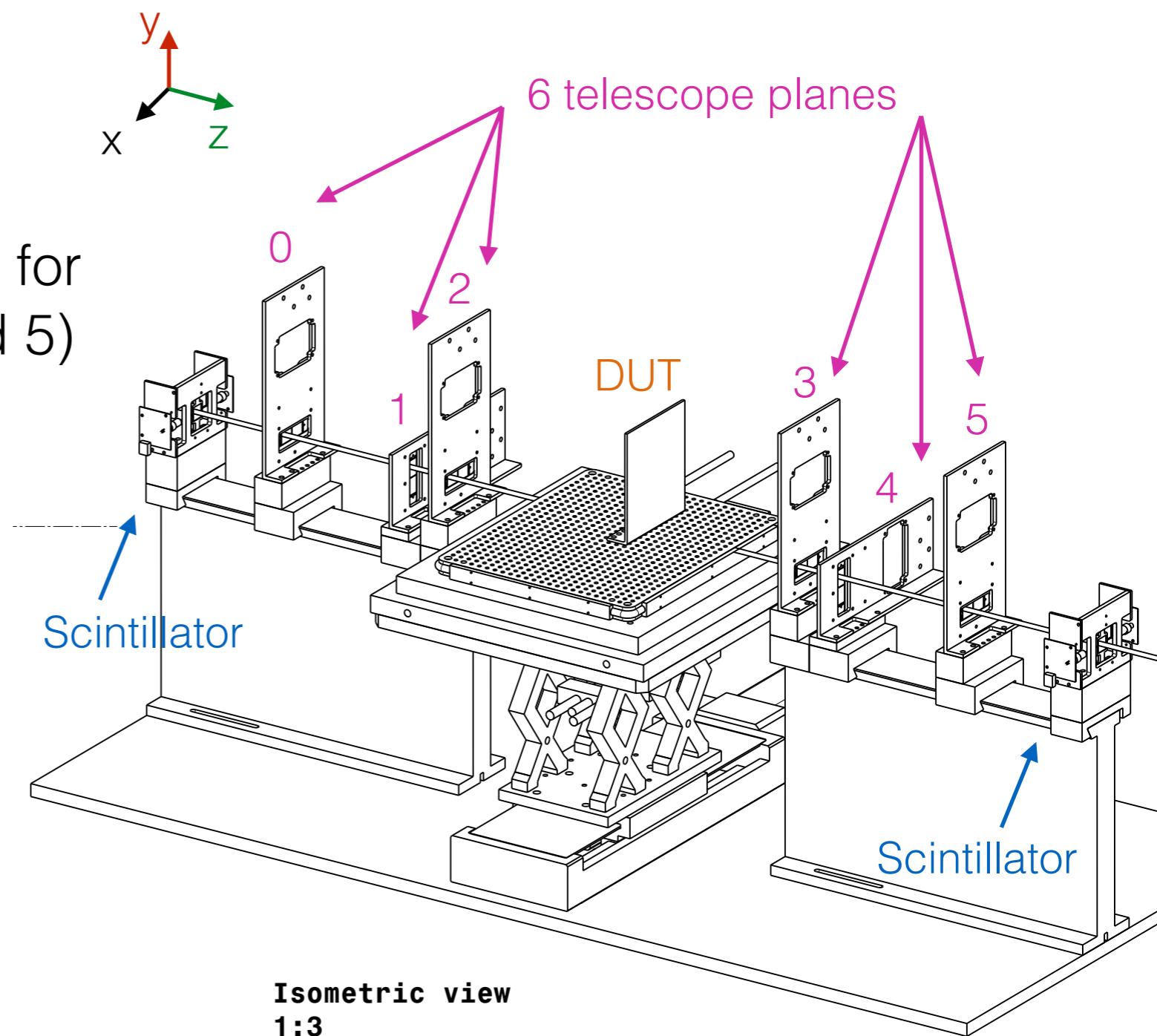
Trento workshop
17/02/15

Overview

- Telescope overview
- HVCMOS v2 and v4 designs and samples
- Efficiency, timing and ToT results
- Threshold and Bias scans

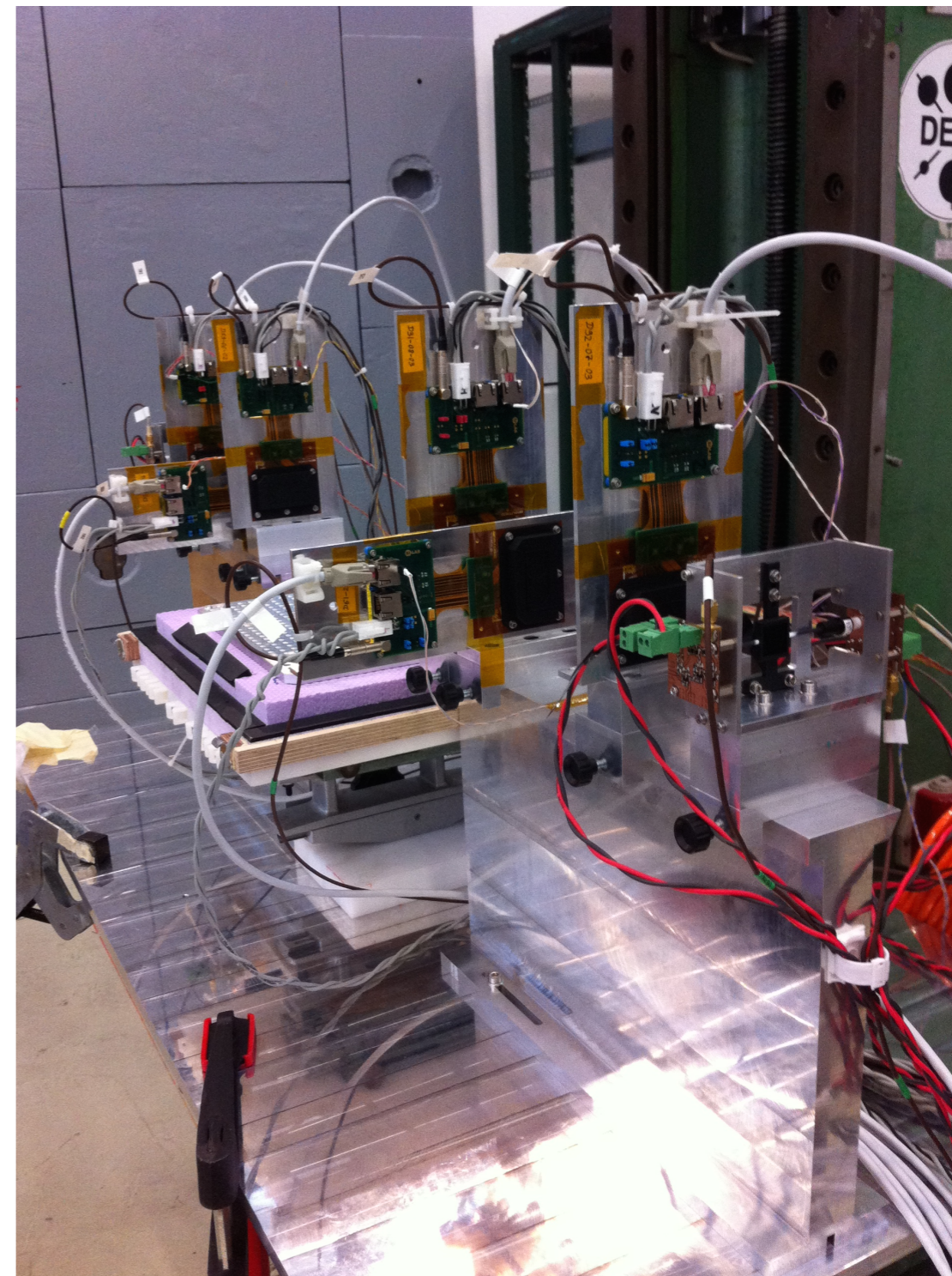
IBL Modules Telescope

- 6 DoubleChip IBL modules (2 x 2 cm²/FE)
- Pixel size of 250 x 50 μm (x-y) for non rotated planes (0,2,3 and 5)
- Trigger on planes 0 and 5 or Scintillators
- ROI can be defined on planes 0 and 5
- RCE readout up to 8 FE (6 telescope planes + 2 DUT) giving thanks to SLAC for the support.



IBL Modules Telescope

- 100 kHz trigger rate during data taking
- >10% of triggers had a hit on the DUT thanks to the ROI definition

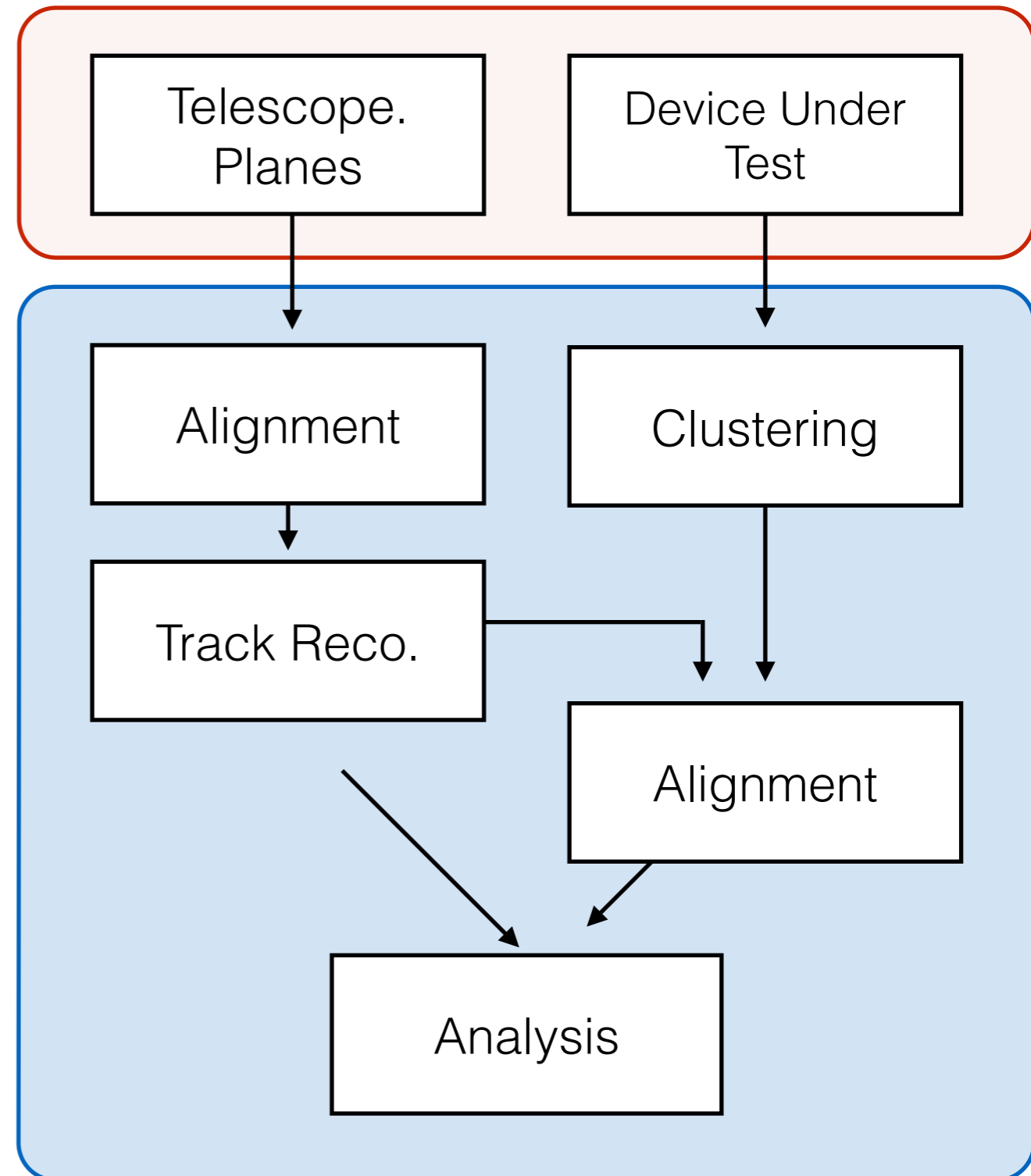


Reconstruction Software

- Reconstruction software: **JUDITH**
- Adapted to handle the telescope geometry (pixel asymmetry and plane rotations) and additional control plots

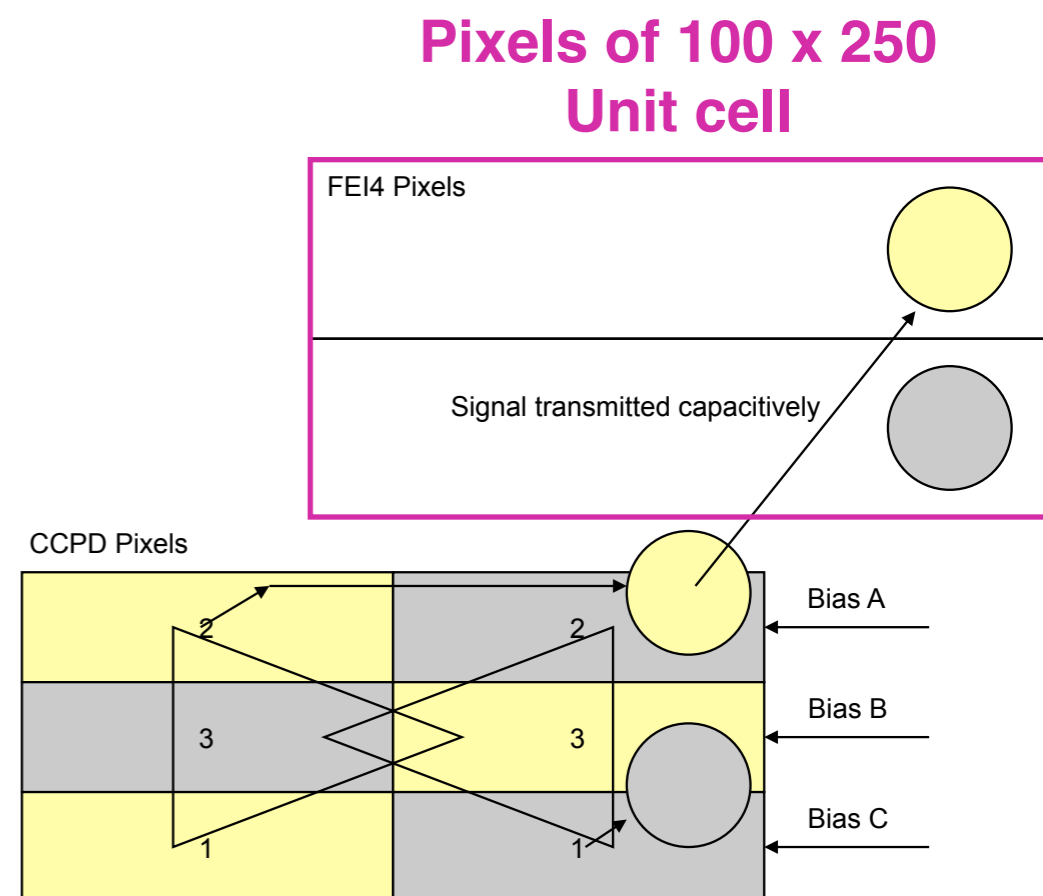
DATA Taking

DATA Reconstruction



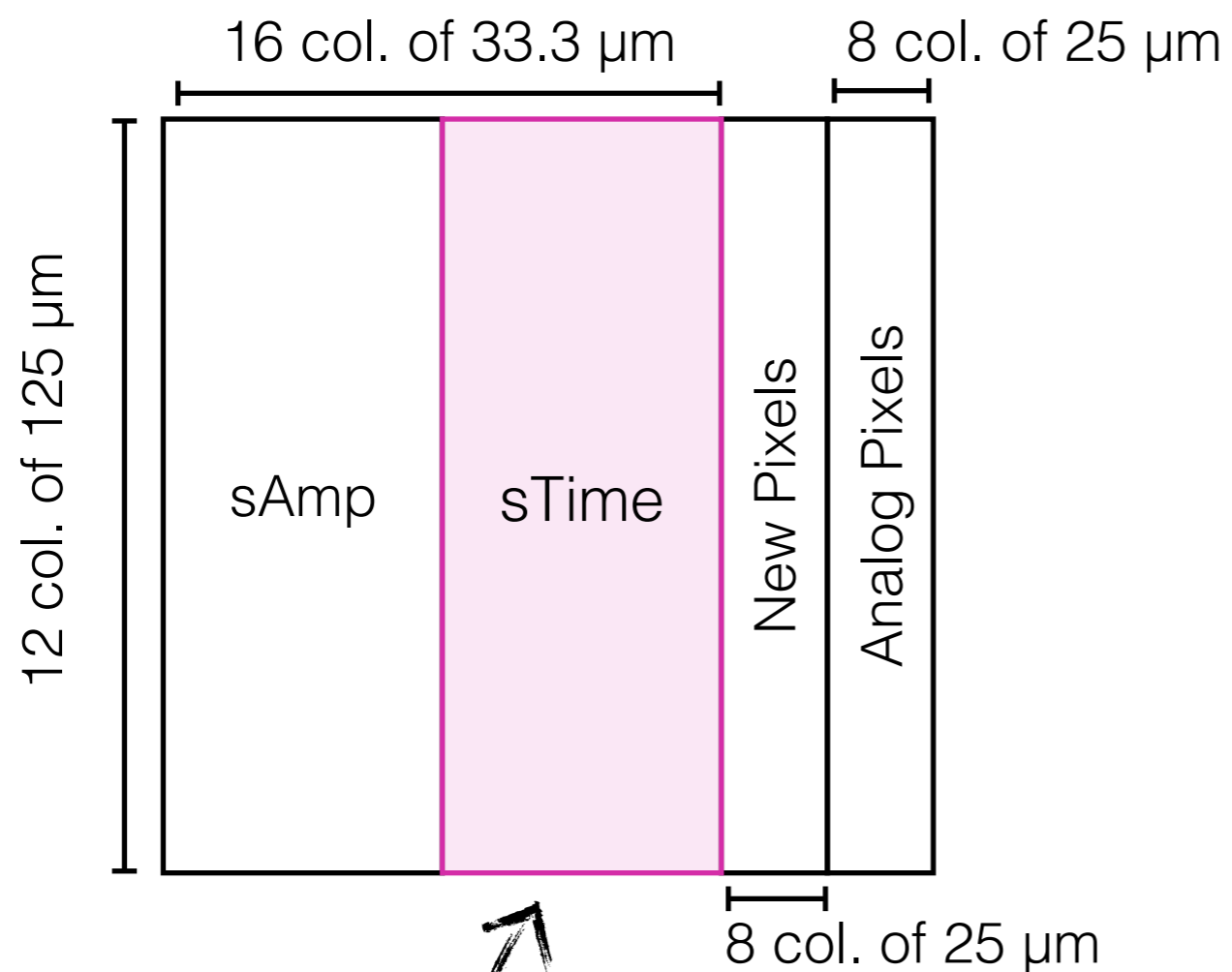
HVCMOS v2

- HV-CMOS version 2
- Sensor Size (2.2 x 4.4 mm²):
 - 36 x 36 sub-pixels (864) each pixel of 33 x 125 μm
- Merged pixels during reconstruction to handle “chest” structure



v4 structure

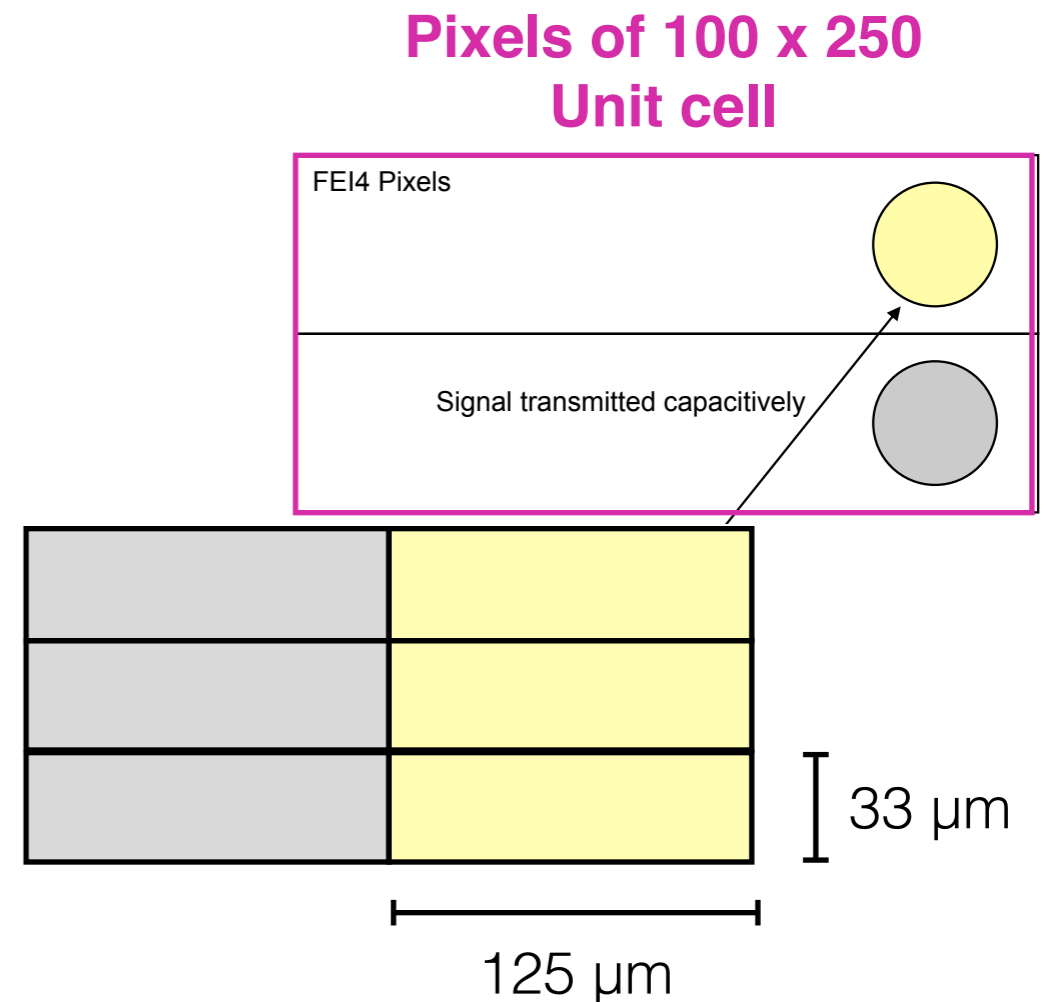
- Several HVCMOS pixels flavours in the HVCMOS v4 structure:



Studied pixels and presented results

v4 structure

- Stime HVCMOS pixels
- Standard pixels with new **voltage-mode amplitude** or pulse length coding
- 16 x 5 **unit cell**, containing 6 HVCMOS pixels 33 x 125 μm
- Different inner pixel connection with respect to v2. Not needed to be taken into account on the reconstruction thanks to the merging



HVCMOS samples

Non Irradiated:

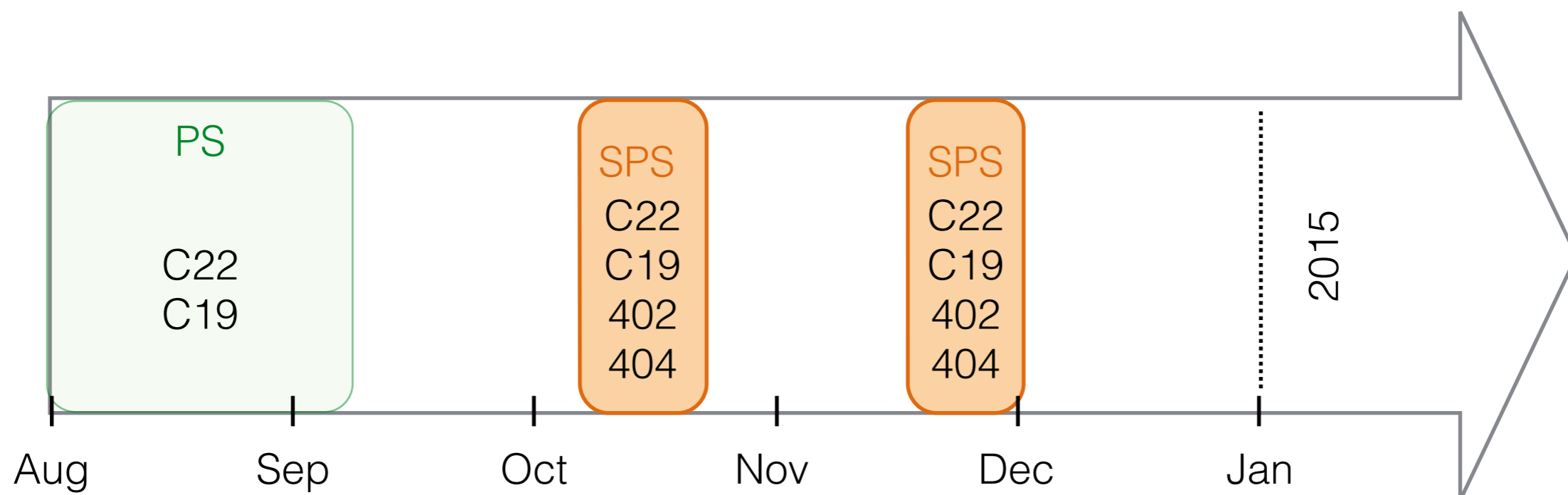
v2: C22

v4: 402

Irradiated:

v2: C19

v4: 404

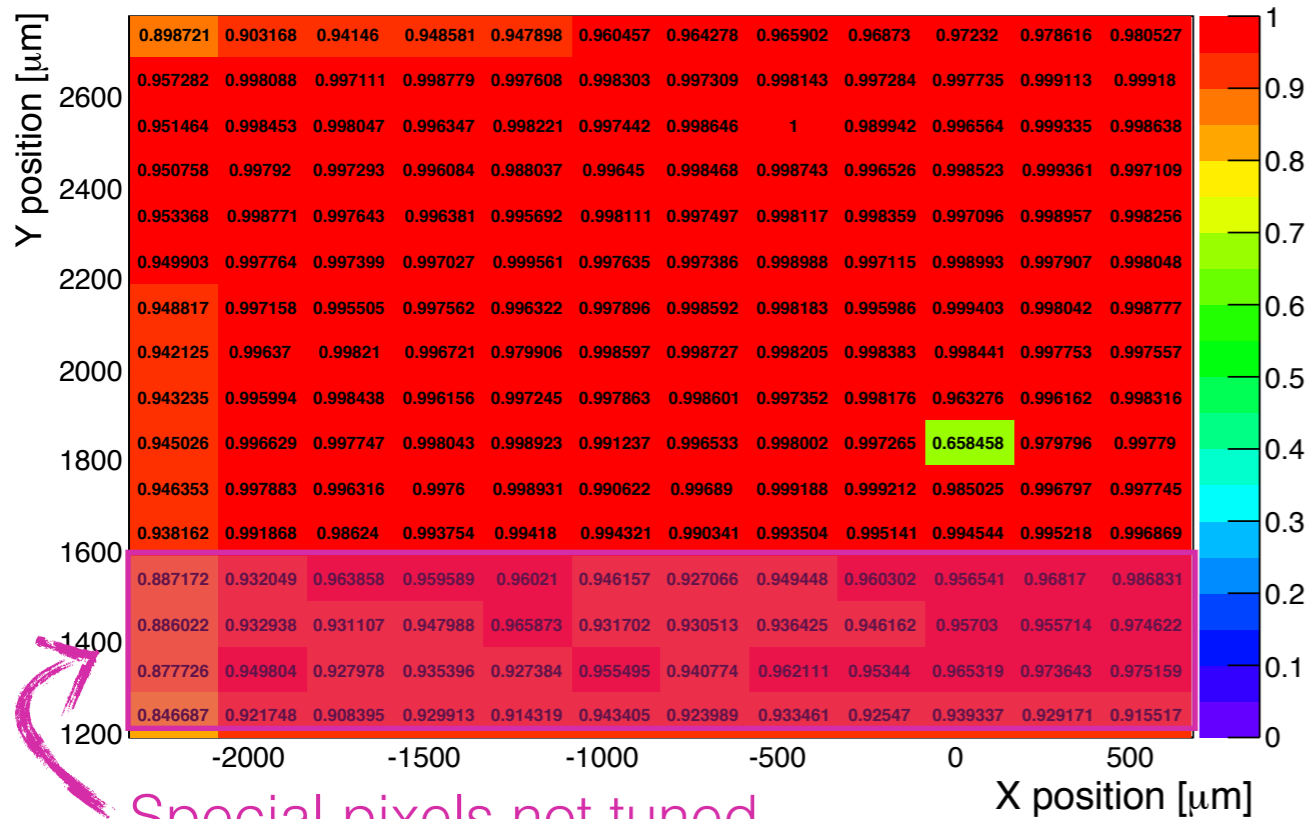


12 Billion triggers during 2014 SPS data taking

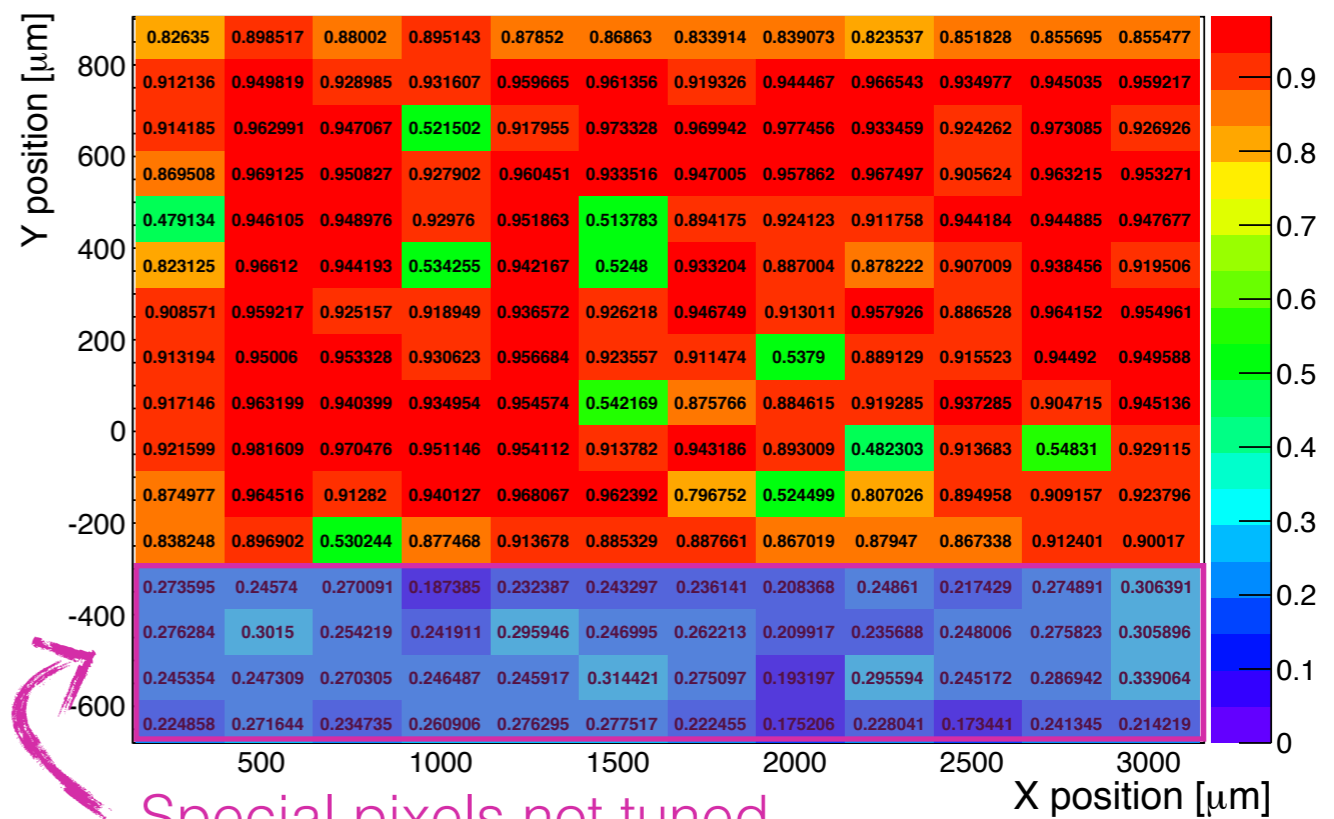
AMS 180 v2 efficiency

C19, unIrradiated
Bias 90 V, Th 0.94 V

C22, $10^{15} \text{ n}_{\text{eq}}/\text{cm}^2$
Bias 80 V, Th 0.94 V

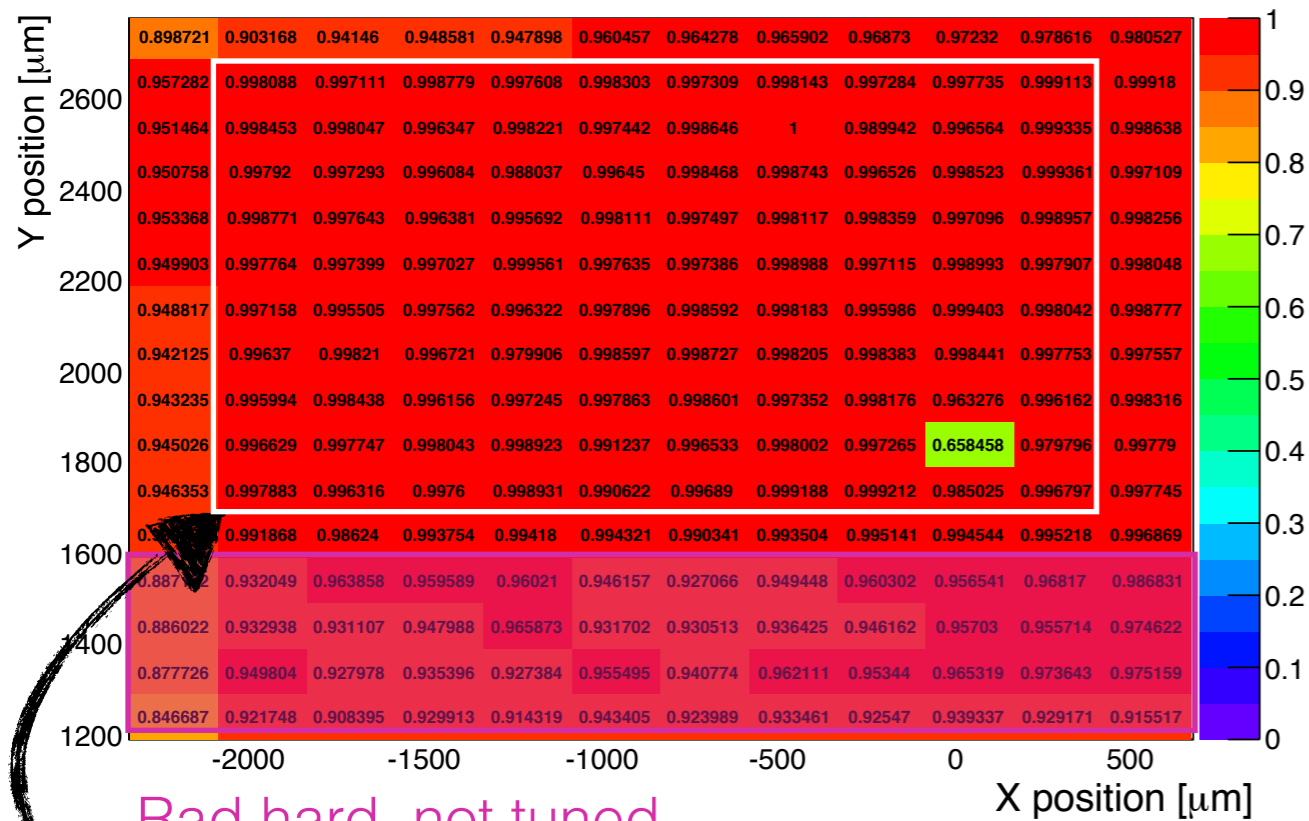


Few HVCMOS pixels showed no output signal



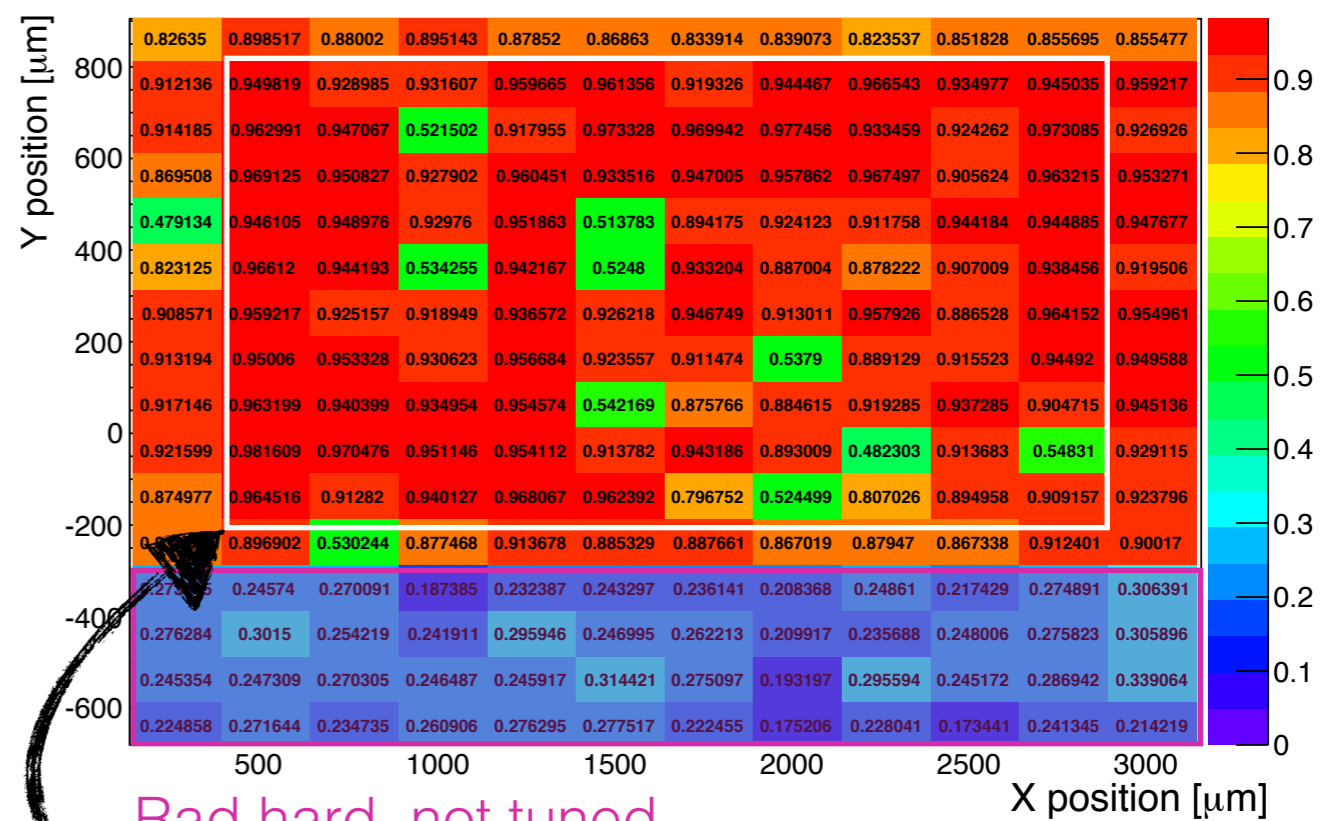
AMS 180 v2 efficiency

C19, unIrradiated
Bias 90 V, Th 0.94 V



Rad hard, not tuned
eff. all Lv1: 99.7%

C22, 10^{15} n_{eq}/cm²
Bias 80 V, Th 0.94 V

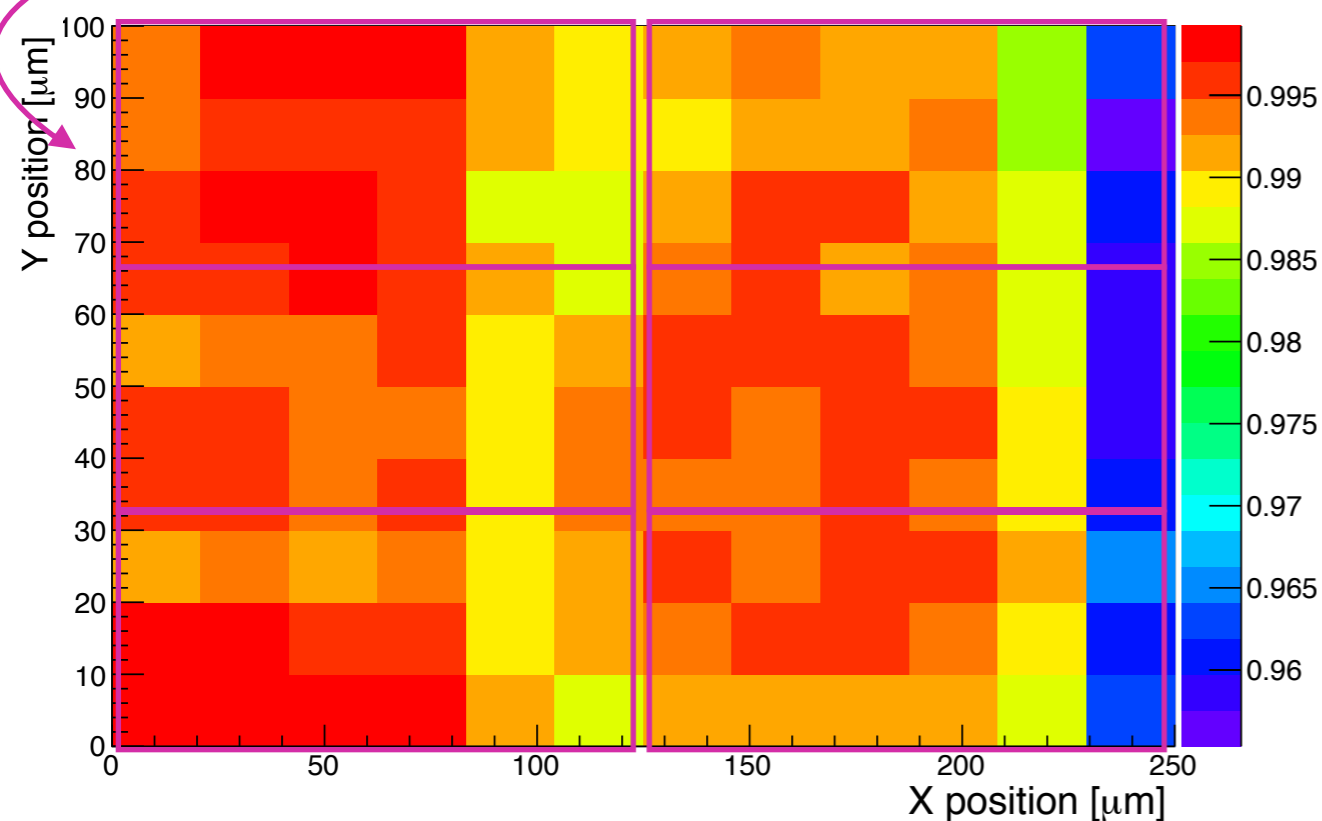


Rad hard, not tuned
eff. all Lv1: 93%

v2 InPixel eff.

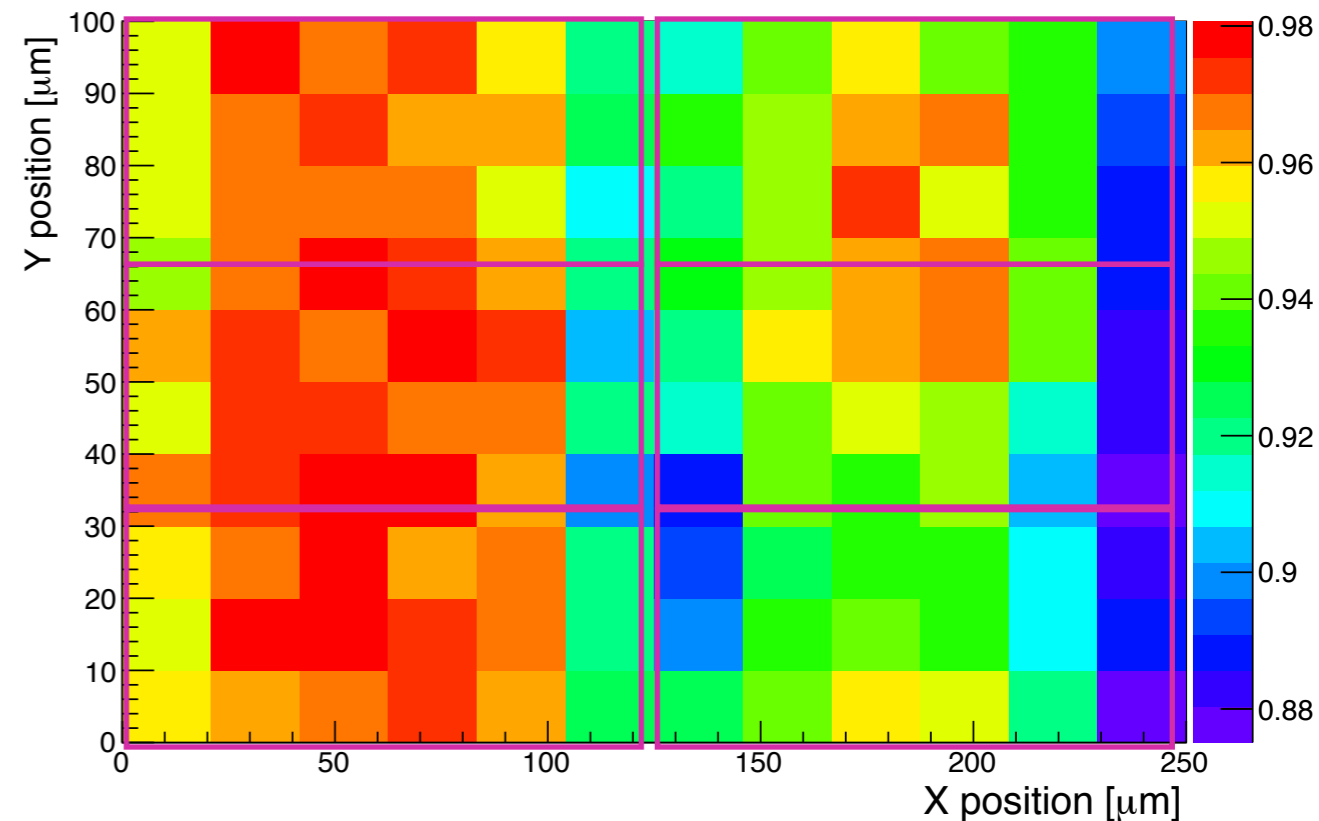
C19, unIrradiated
Bias 90 V, Th 0.94 V

2x3 HVCMOS pixels in 1 unit-cell



eff. all Lv1: 99.7%

C22, 10^{15} n_{eq}/cm²
Bias 80 V, Th 0.94 V

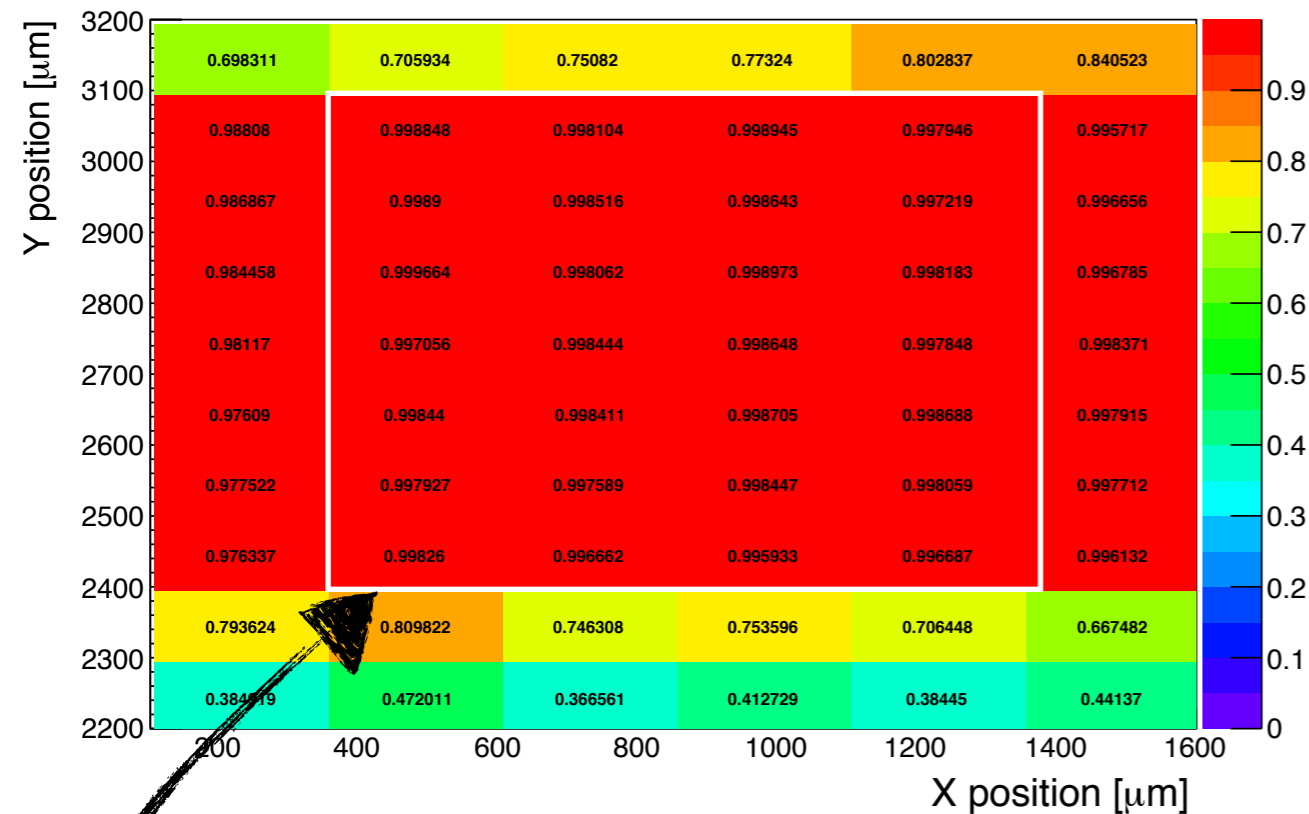


eff. all Lv1: 93%

v4 Global eff.

402, unIrradiated
Bias 12 V, Th 0.84 V

10M events

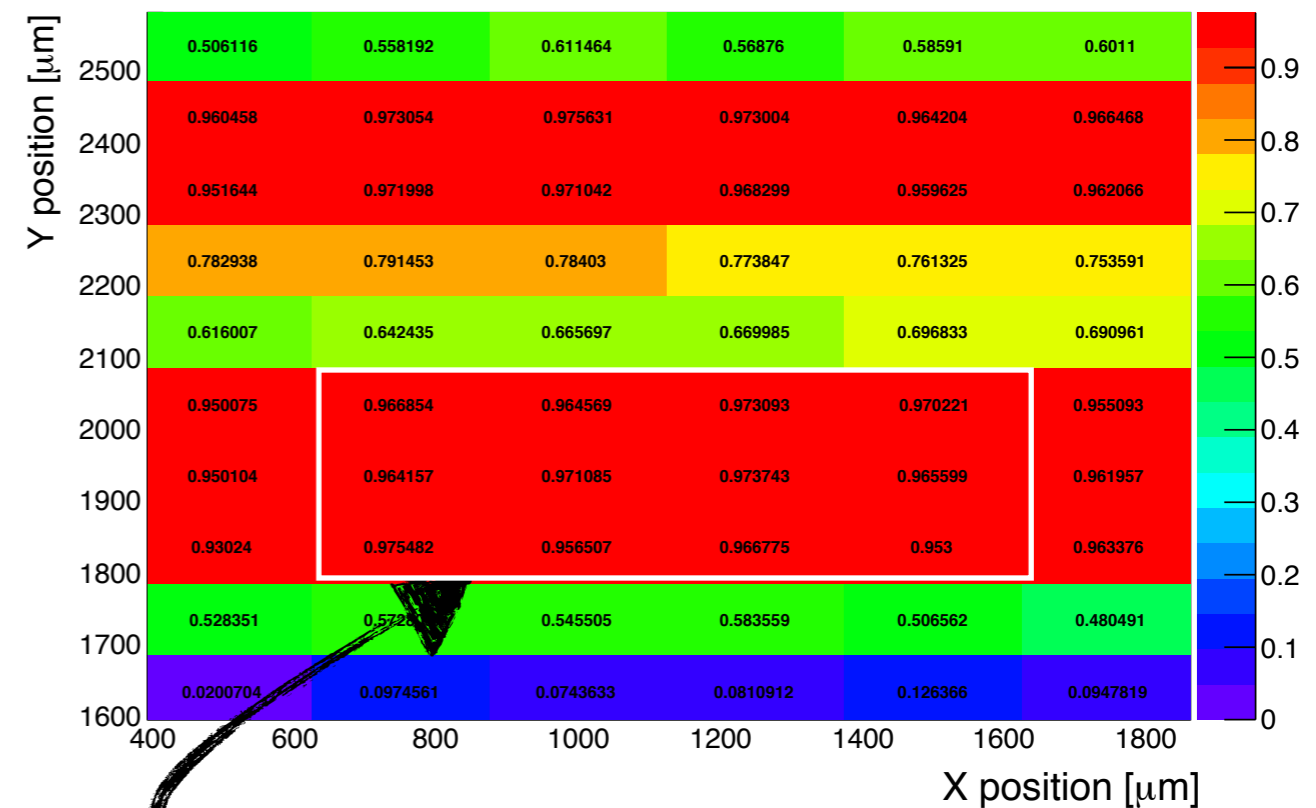


eff. all Lv1: 99.7%

404, 10^{15} n_{eq}/cm²
Bias 30 V, Th 0.84V

2M events

1 HVCMOS Row was off during data taking

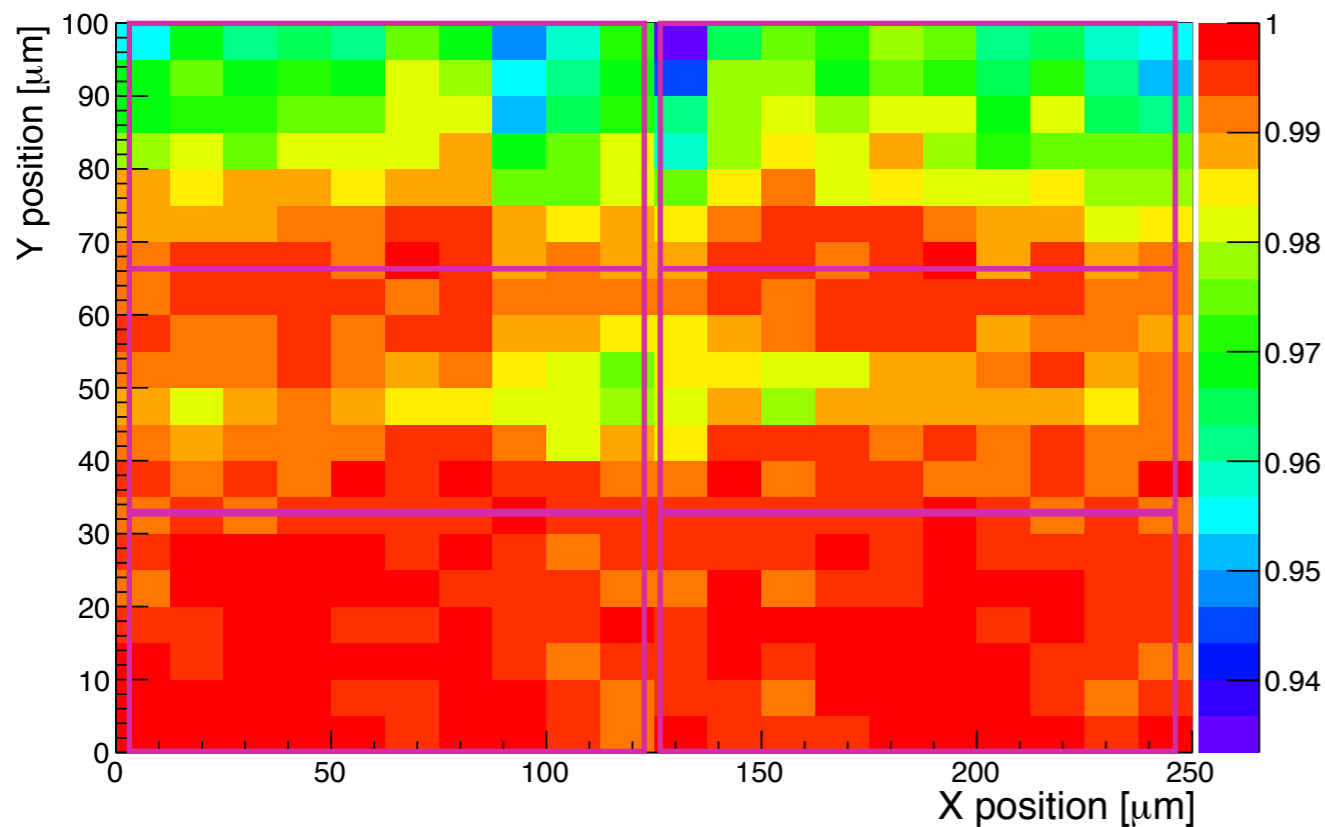


eff. all Lv1: 96.2%

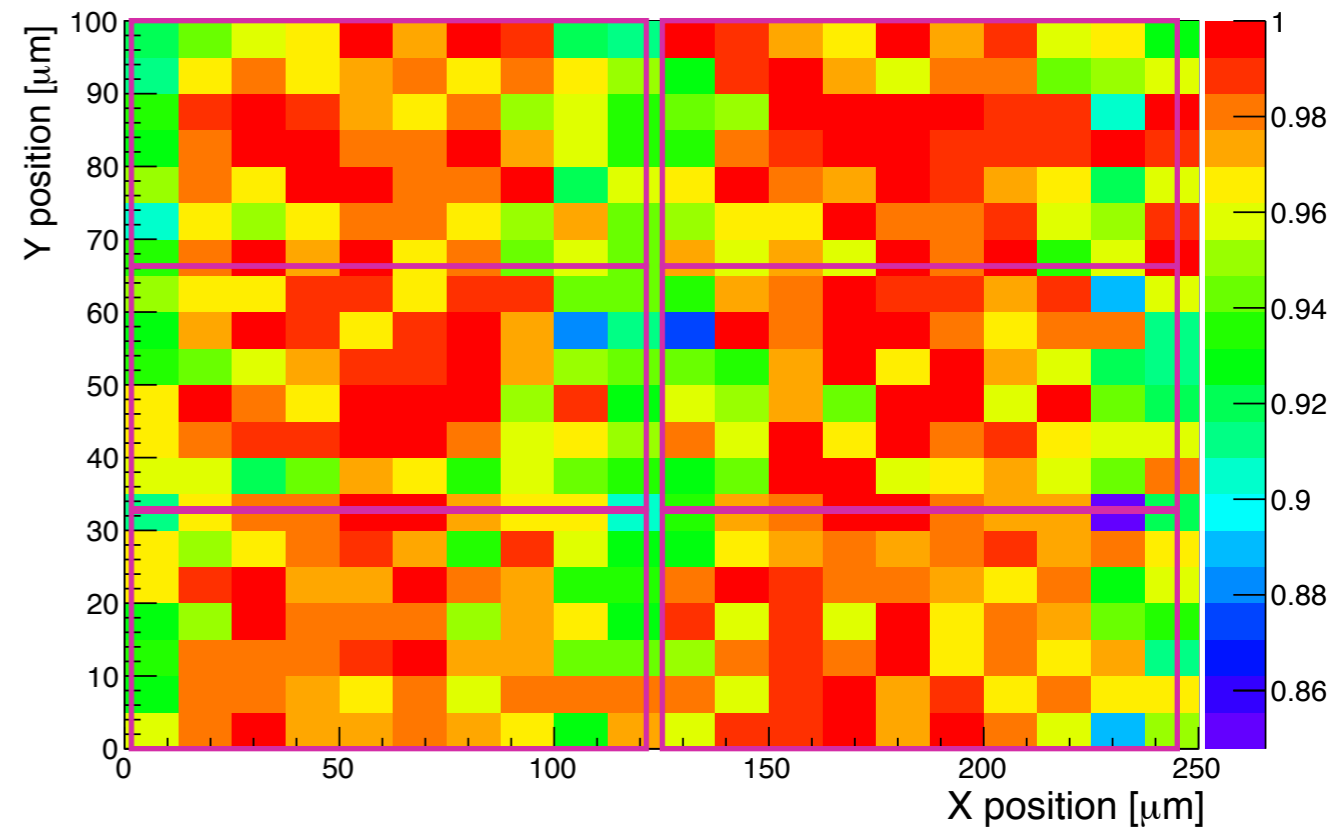
v4 InPixel eff.

402, unIrradiated
Bias 12 V, Th 0.84 V

404, 10^{15} n_{eq}/cm^2
Bias 30 V, Th 0.84V



Possible misalignment on Y axis observed

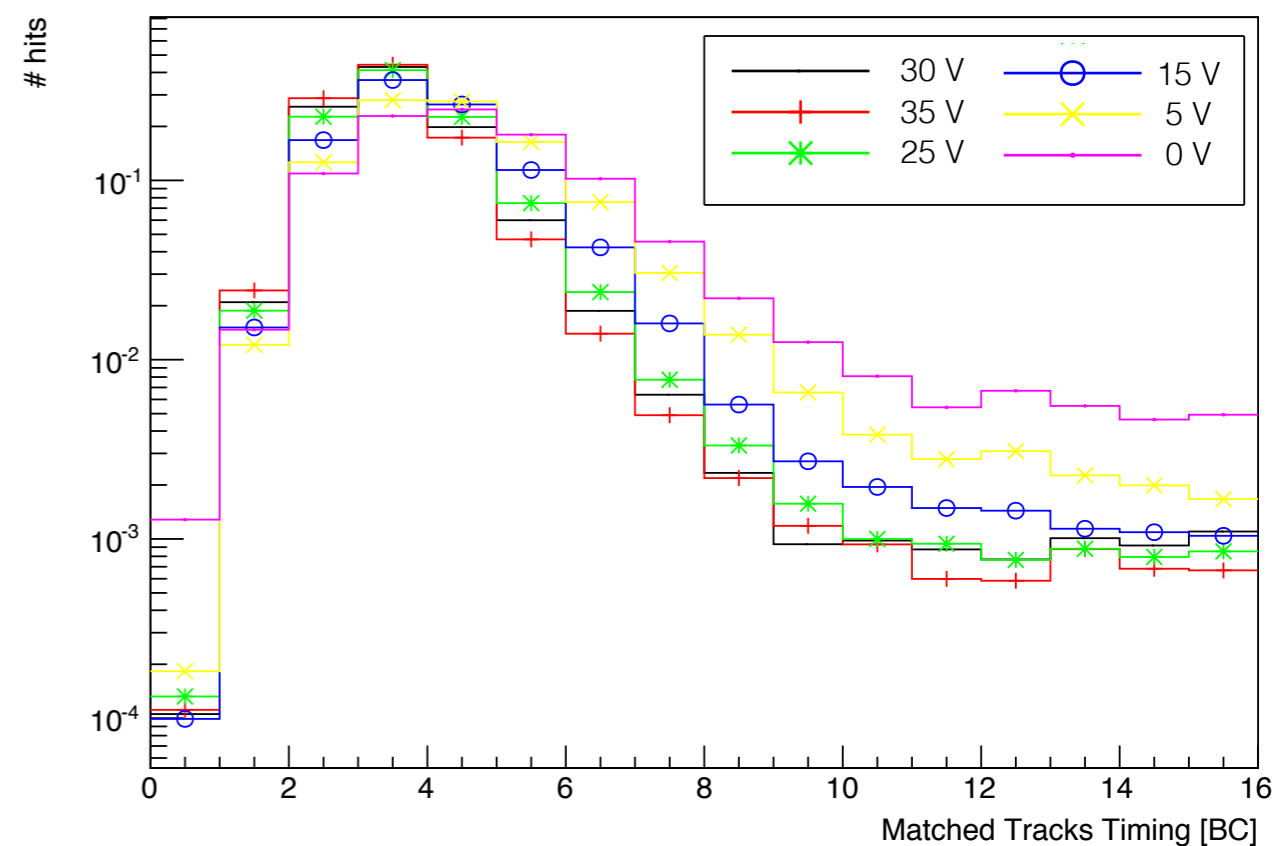
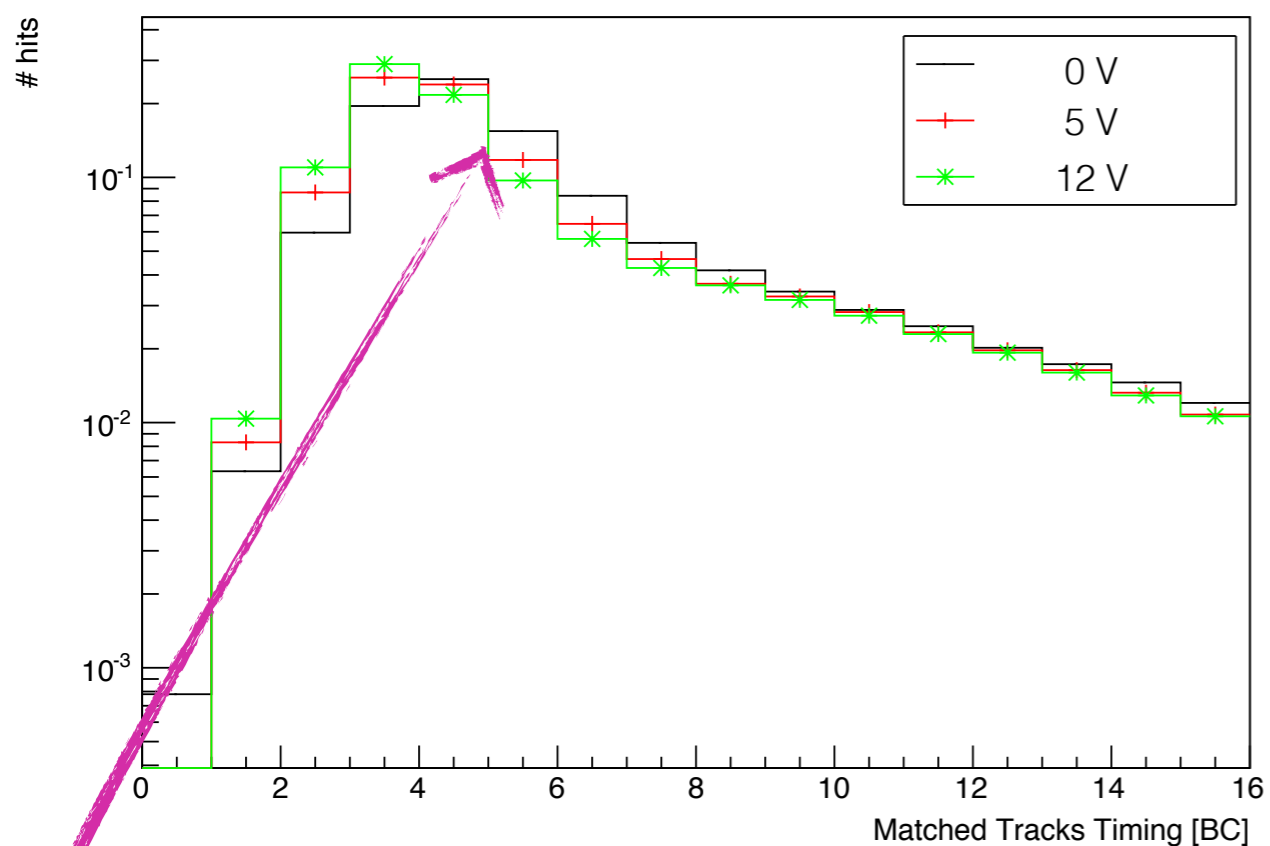


InPixel lower efficiency in the HVCMOS pixel boundaries

v4 Timing vs Bias V.

402, unIrradiated
Th 0.84 V

404, 10^{15} n_{eq}/cm²
Th 0.84V

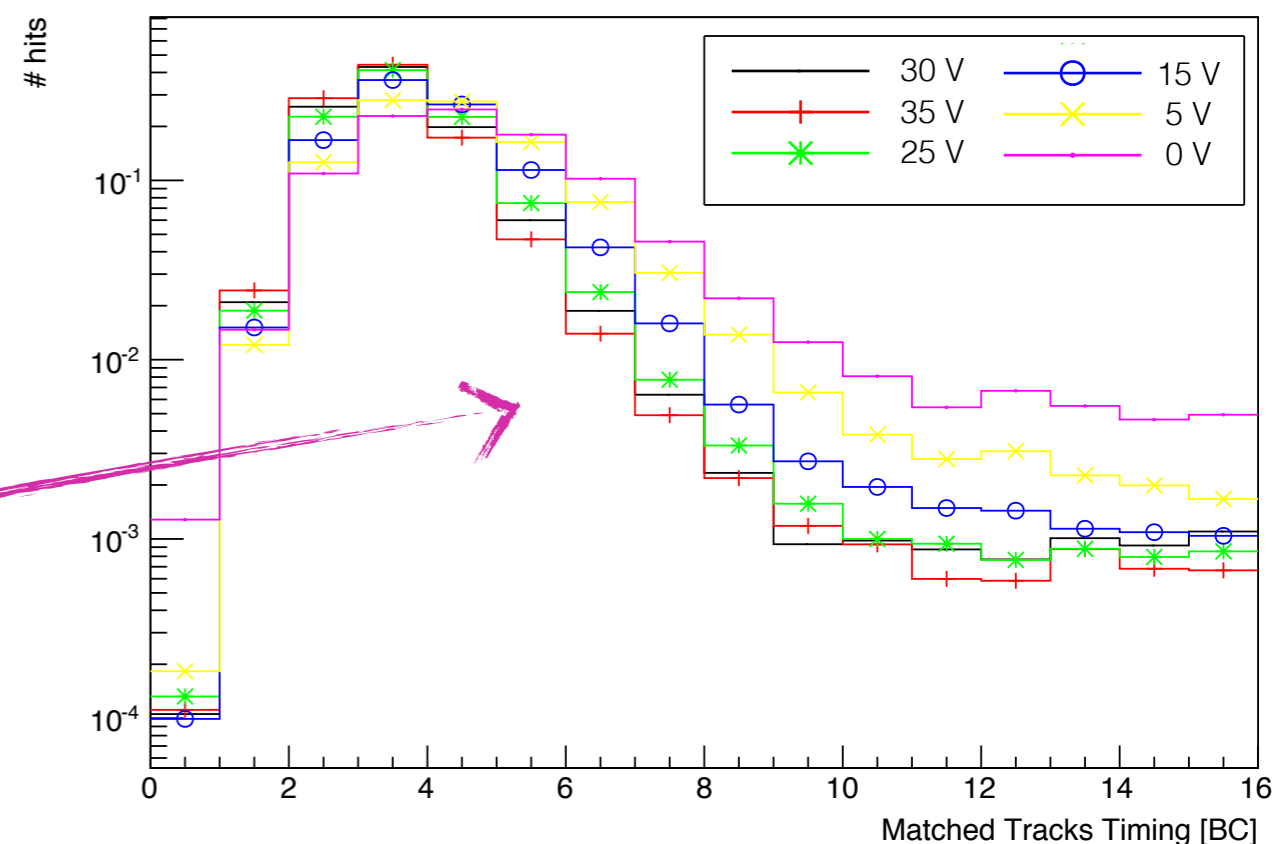
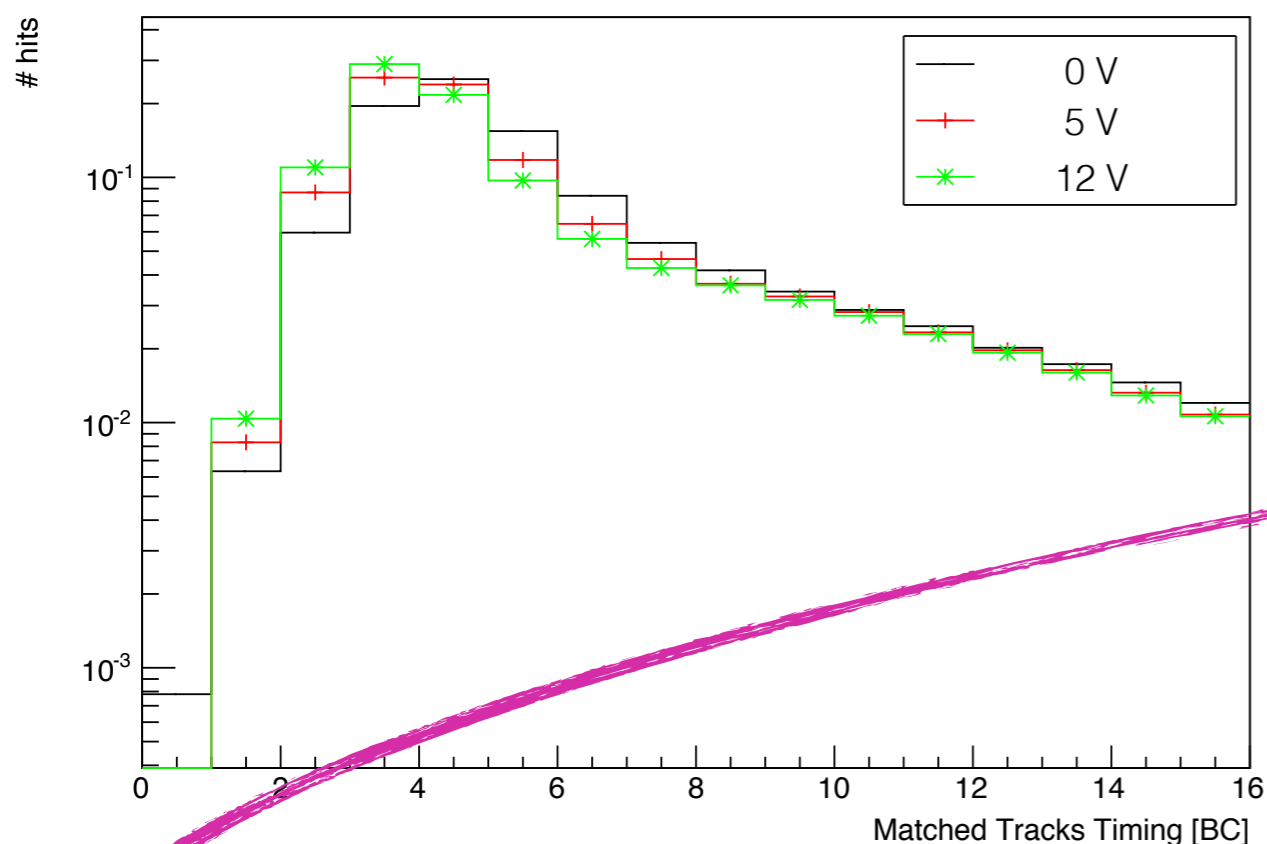


Higher Bias show sharper timing distributions

v4 Timing vs Bias V.

402, unIrradiated
Th 0.84 V

404, 10^{15} n_{eq}/cm²
Th 0.84V

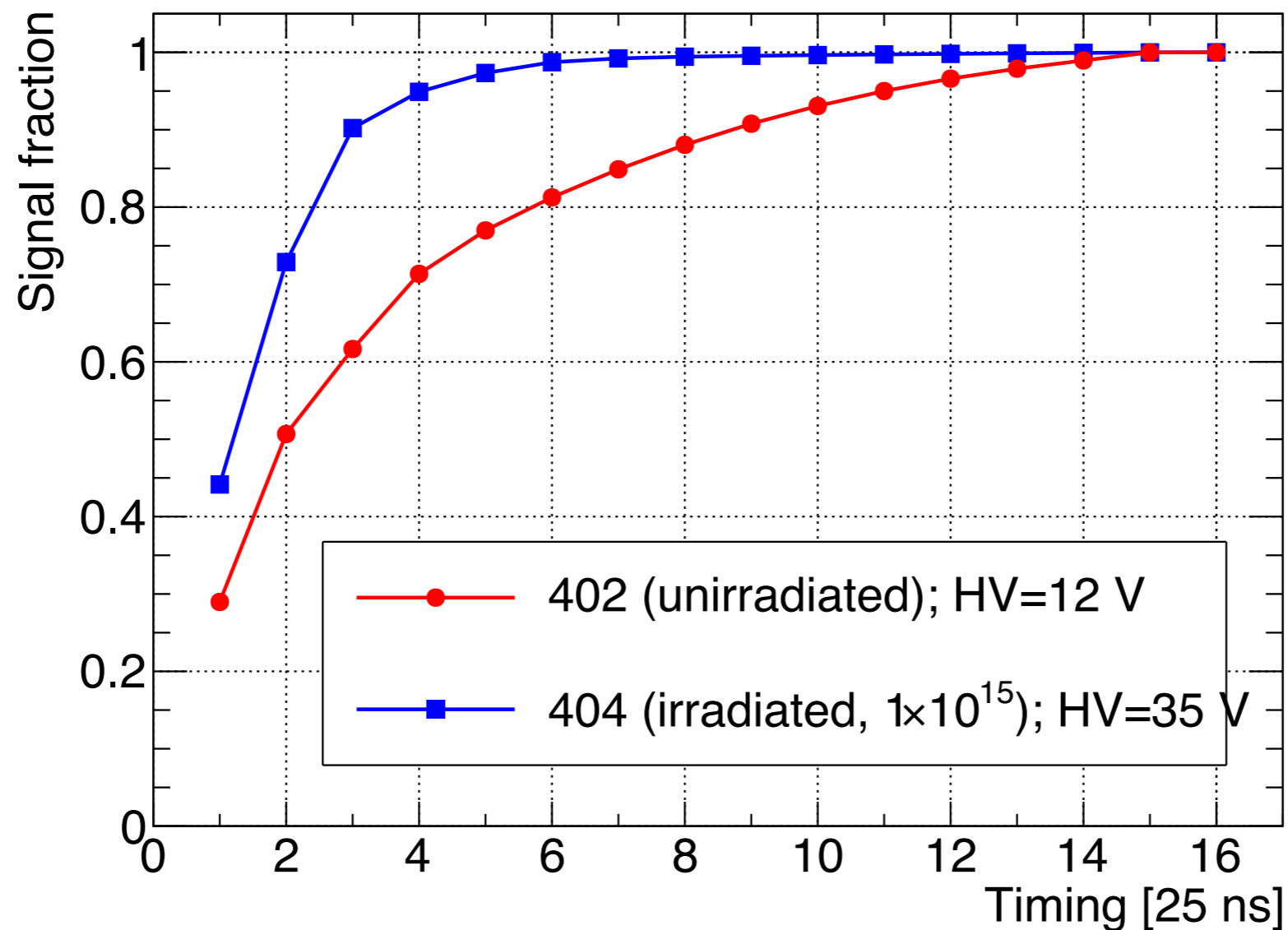


Higher Bias show sharper timing distributions

Higher Bias show smaller tails, Indication for possible diffusion effect.

v4 Timing vs Bias V.

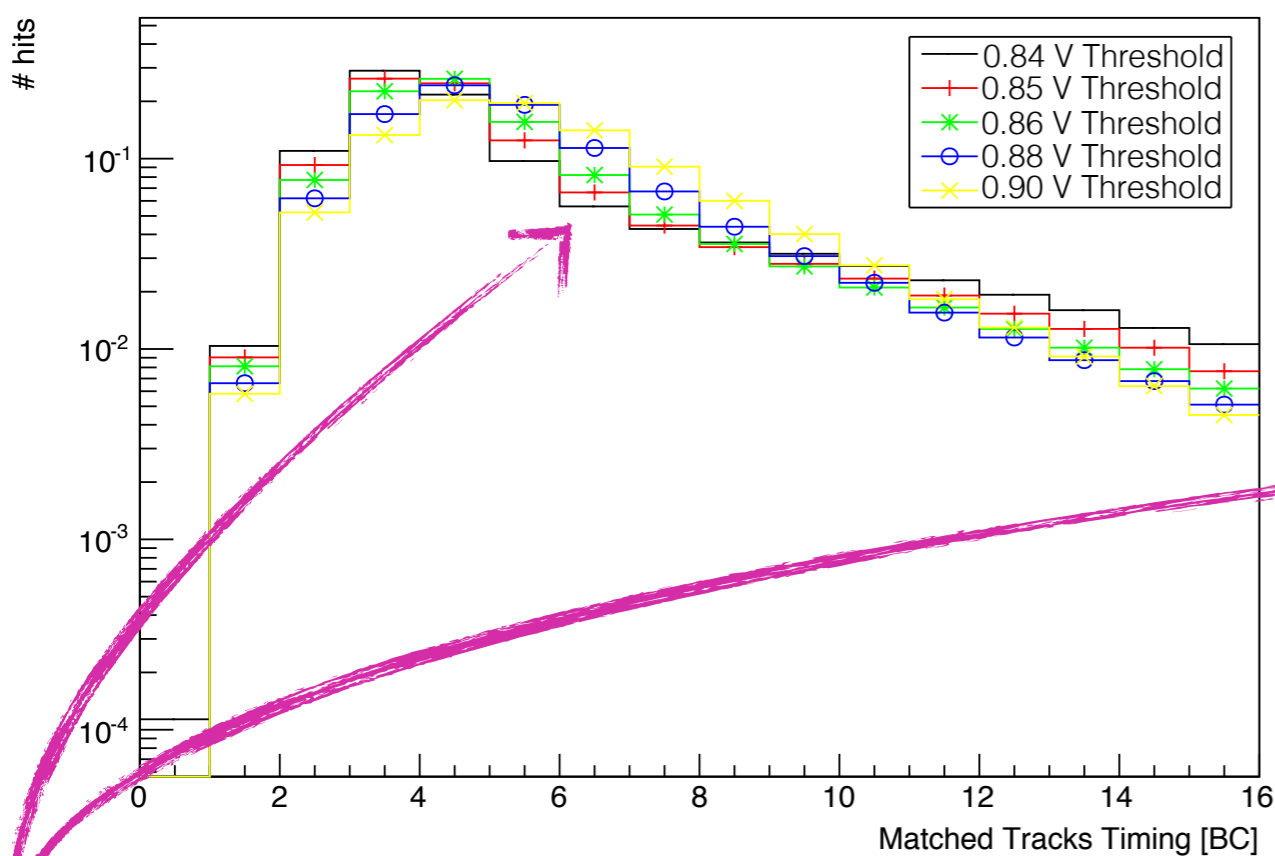
Integrated signal fraction over X of the most populated bins, from 1 single BC to 16 BC in 25 ns units



v4 Timing vs Threshold.

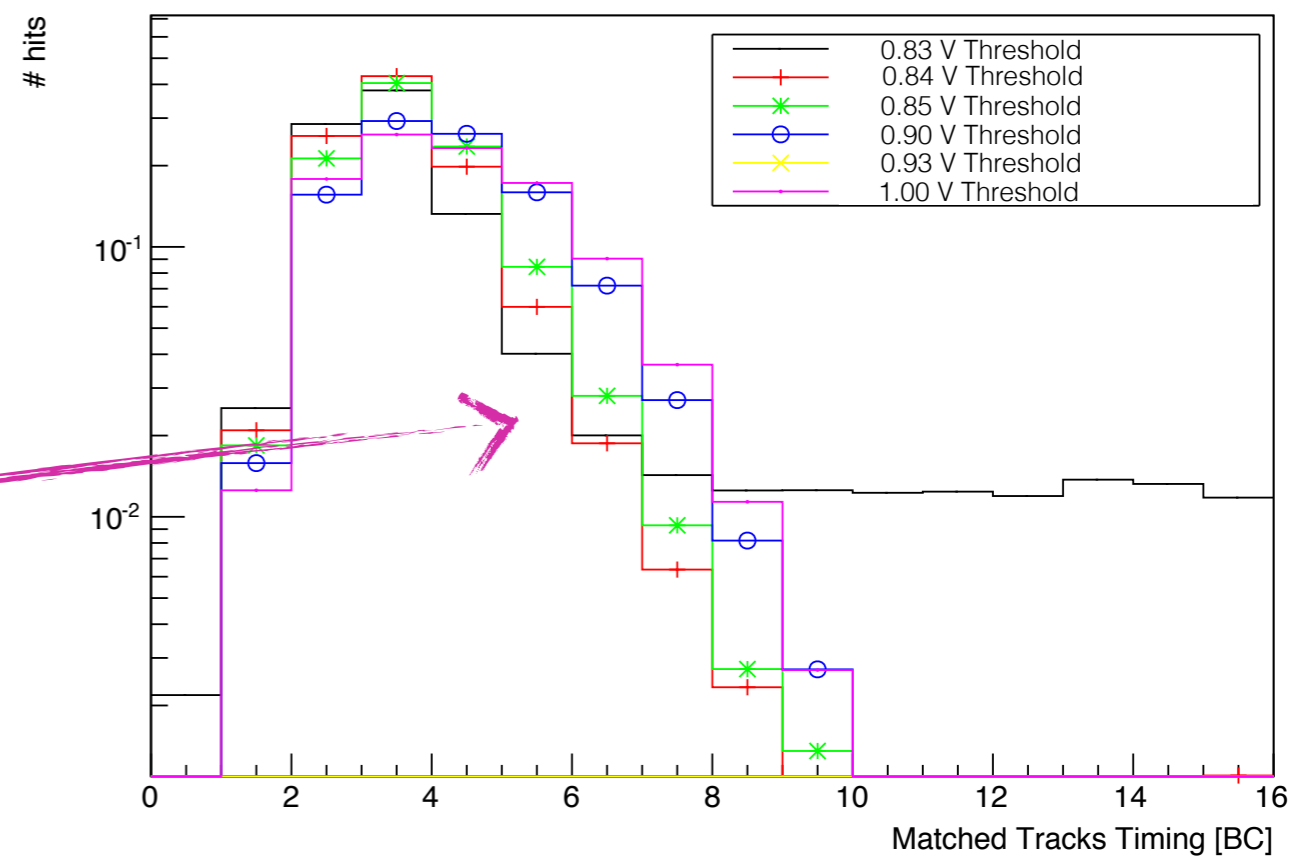
402, unIrradiated
Th 0.84 V

DUT - Plane0 [Matched tracks : Timing]



404, 10¹⁵ n_{eq}/cm², Bias 30 V

DUT Plane0 Matched Tracks Timing

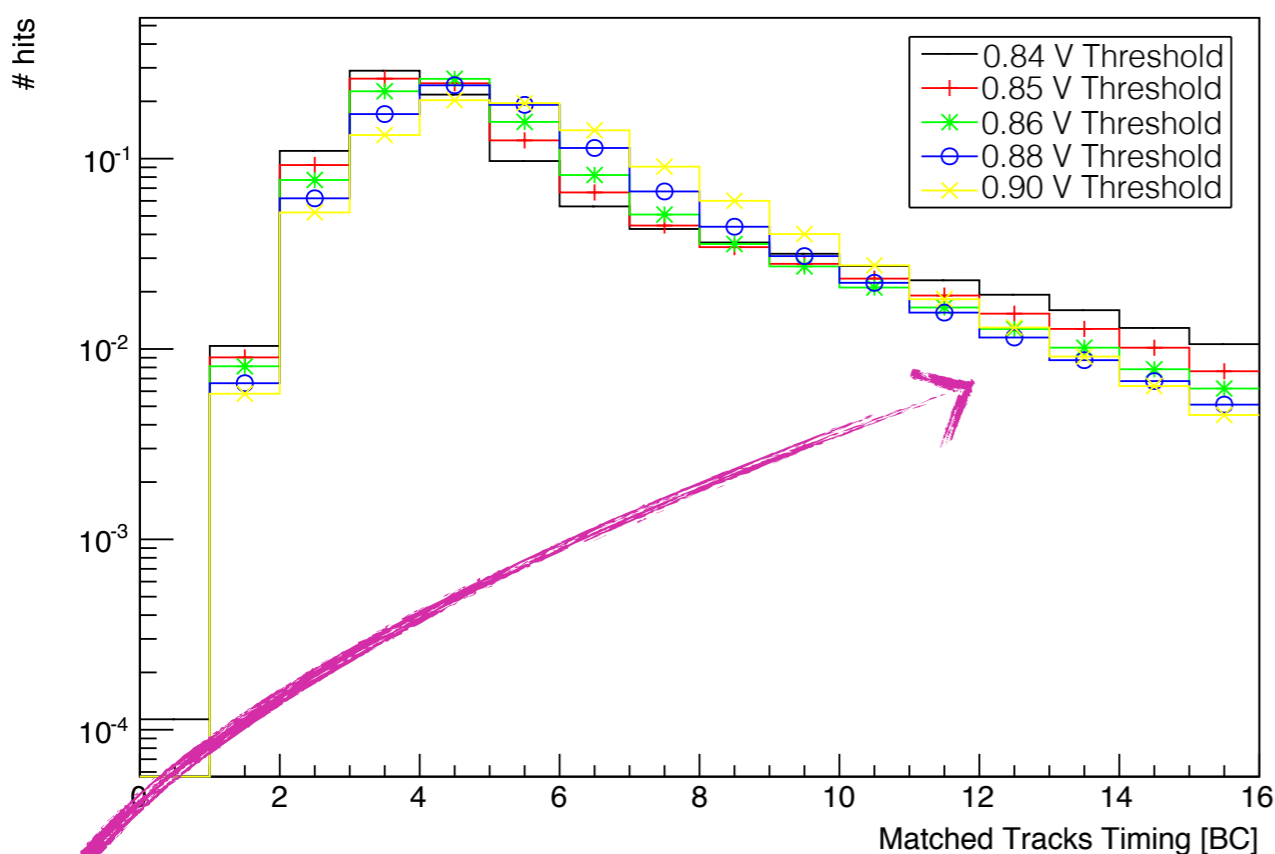


Low threshold show smaller tails, indication of a **time-walk effect**.

v4 Timing vs Threshold.

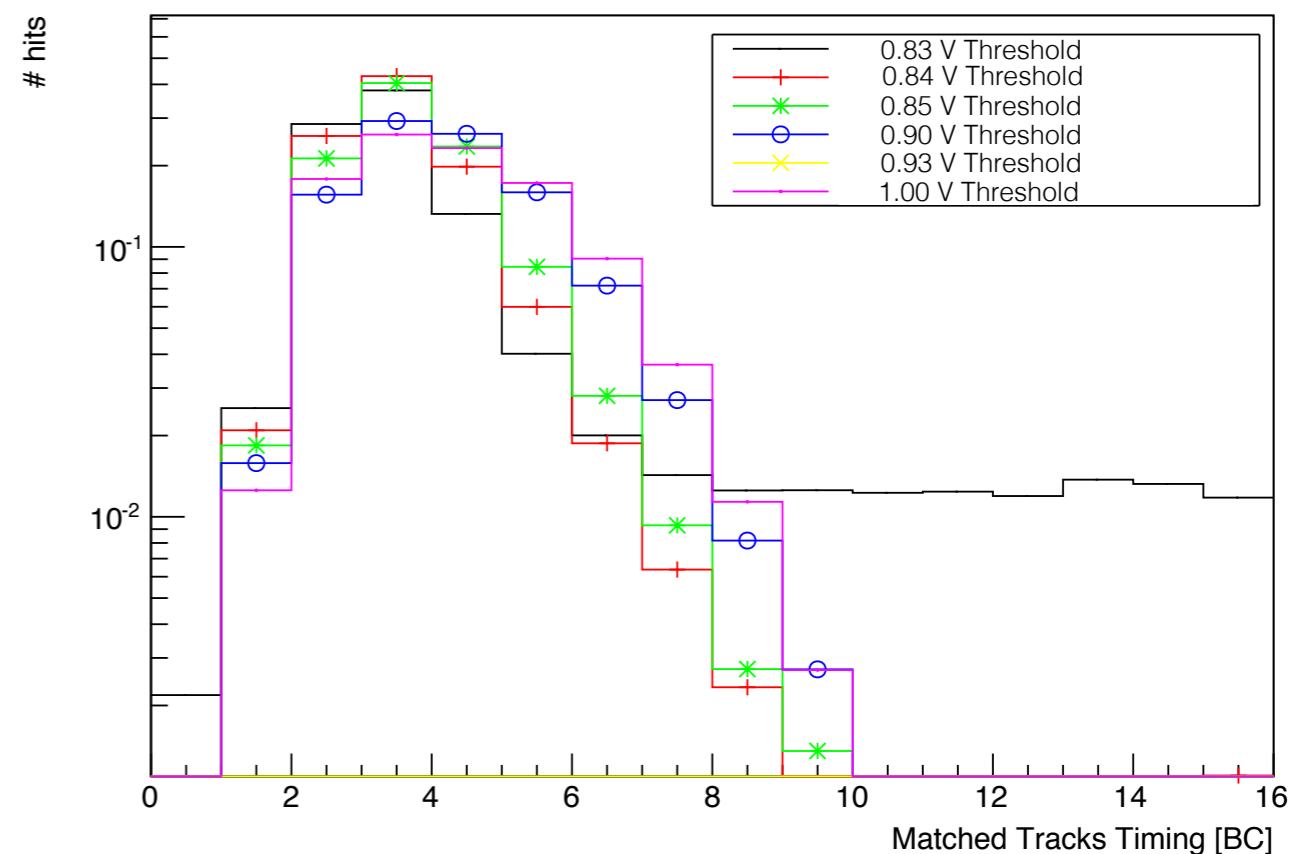
402, unIrradiated
Th 0.84 V

DUT - Plane0 [Matched tracks : Timing]



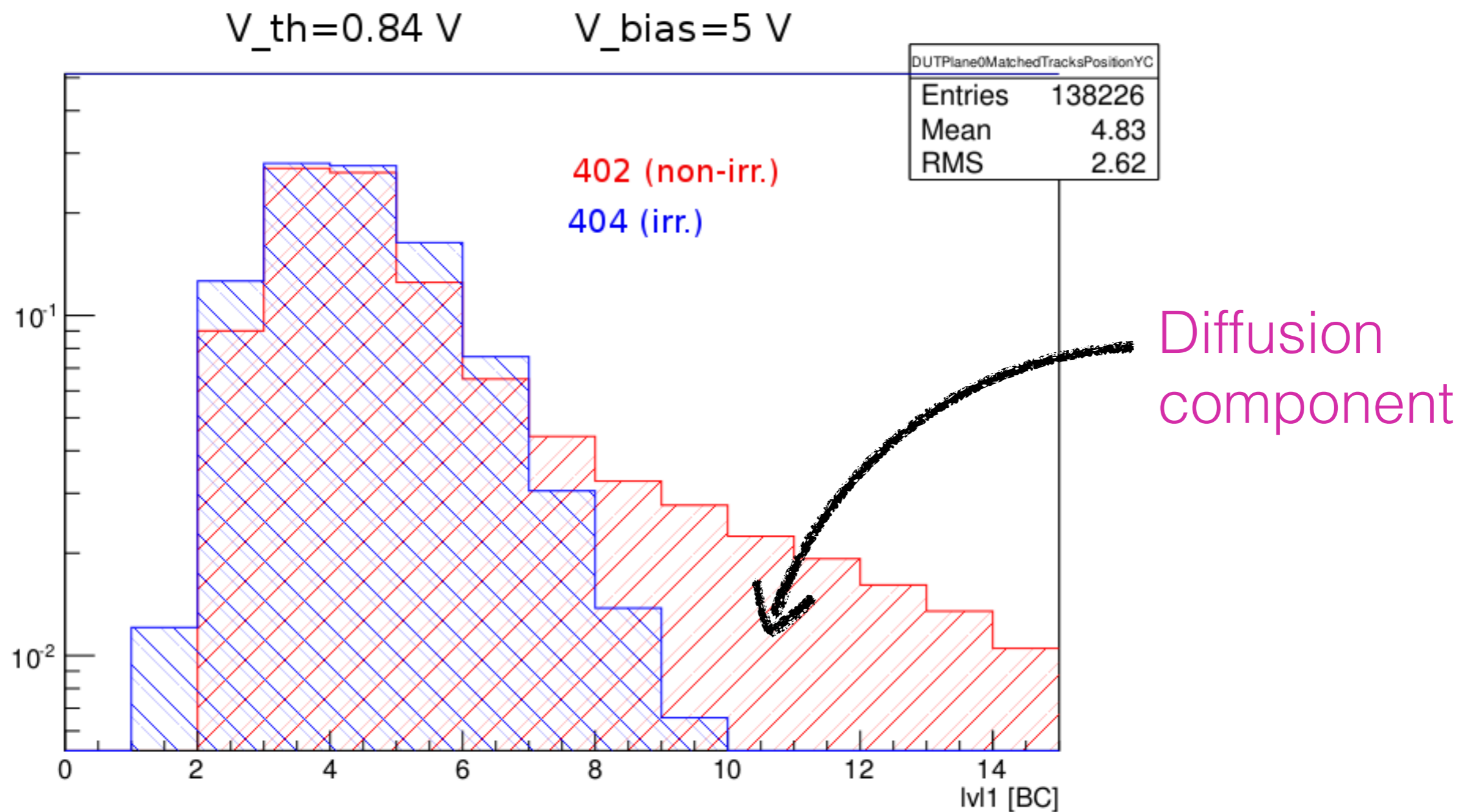
404, 10^{15} n_{eq}/cm², Bias 30 V

DUT Plane0 Matched Tracks Timing



Low threshold show smaller tails, indication of a time-walk effect.
High threshold reduces the diffusion contribution (low Amplitude).

v4 Timing comparison

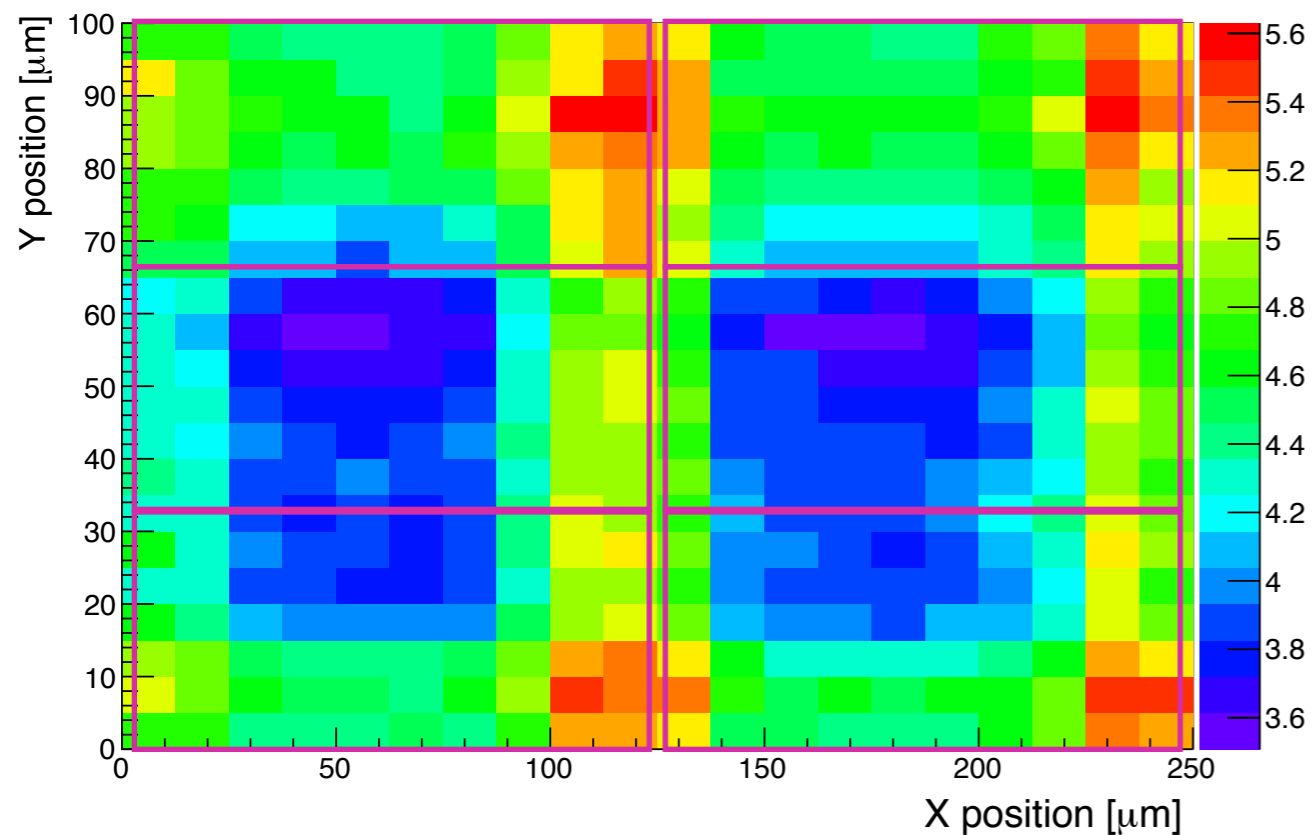


v4 InPixel Timing

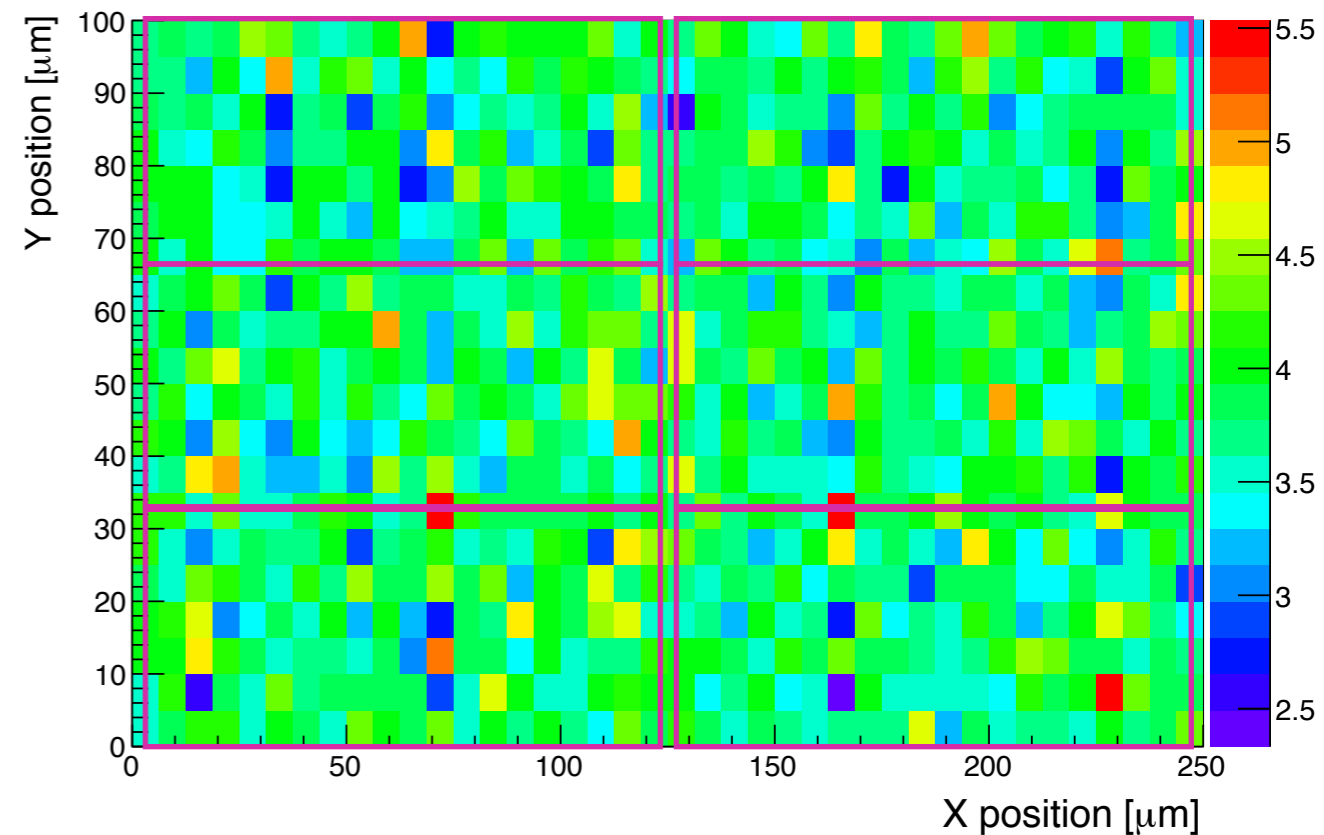
402, unIrradiated
Bias 12 V, Th 0.84 V

404, 10^{15} n_{eq}/cm²
Bias 30 V, Th 0.84V

DUT Plane0 In Pixel Timing Map



DUT Plane0 In Pixel Timing Map

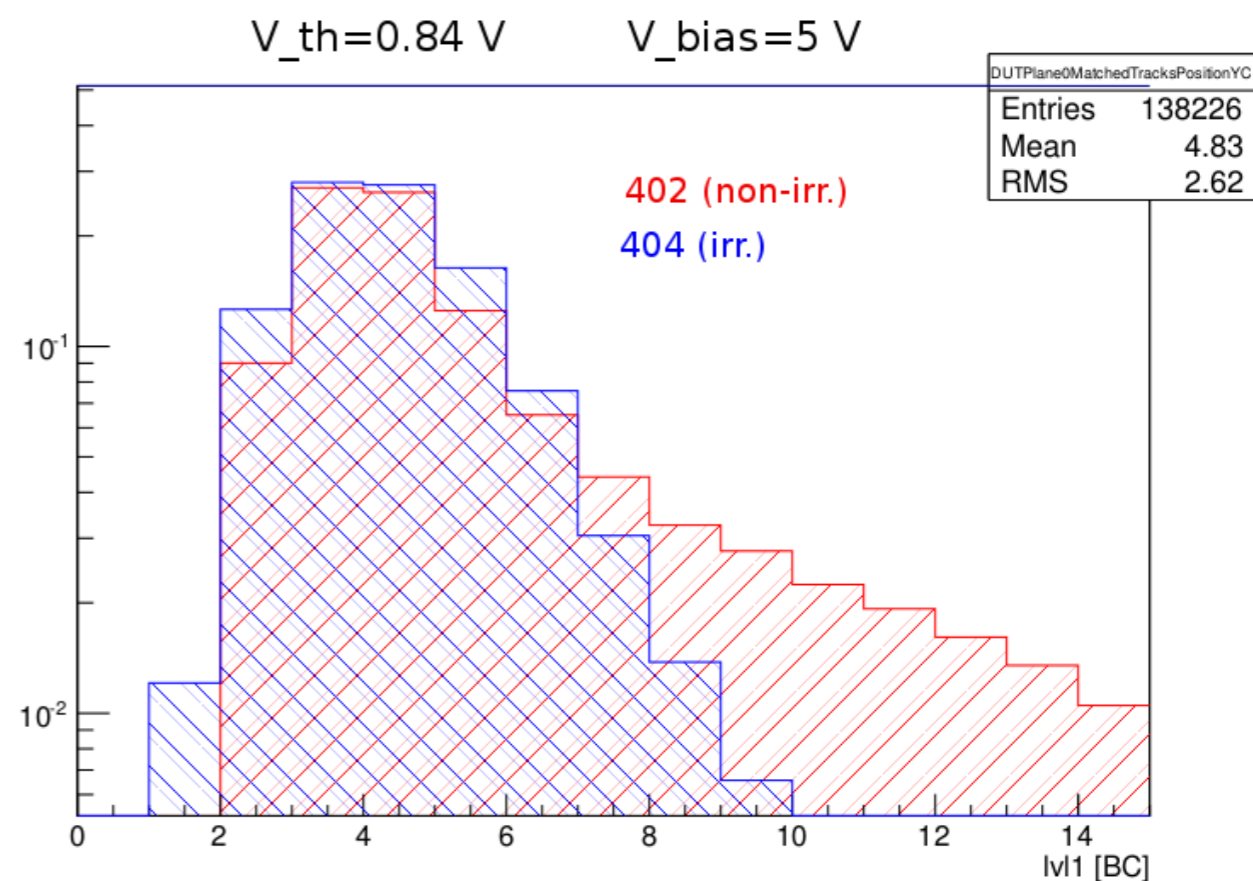
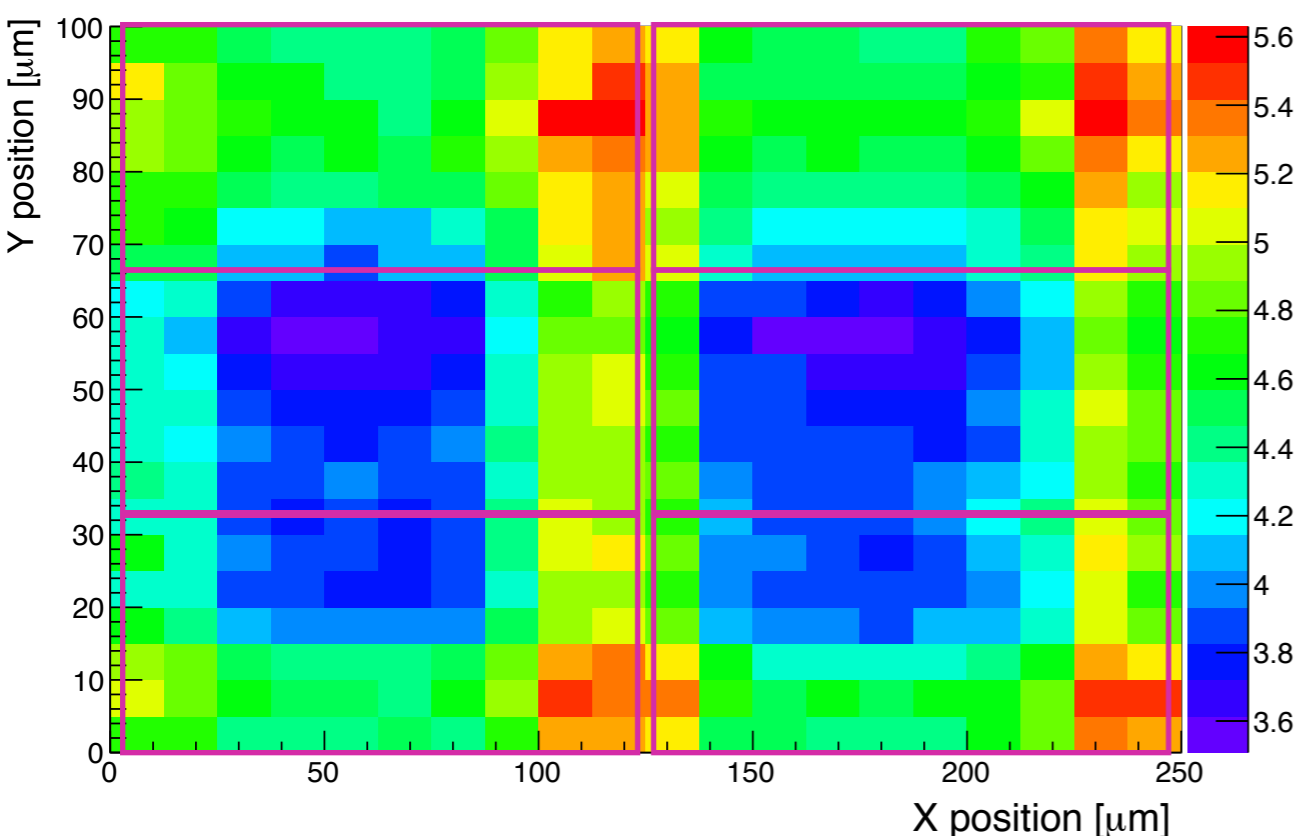


InPixel Timing inhomogeneities showing later events in the HVCMOS pixel boundaries. Not present on irradiated sample

v4 InPixel Timing

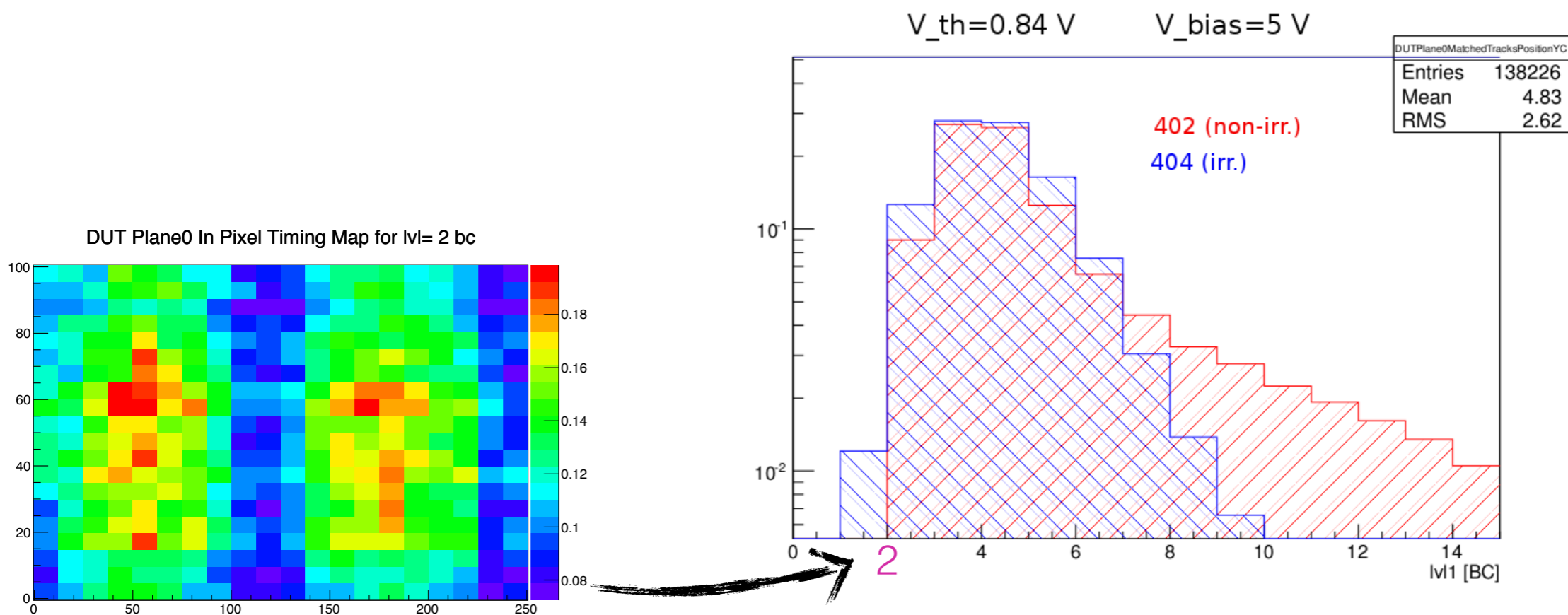
402, unIrradiated
Bias 12 V, Th 0.84 V

DUT Plane0 In Pixel Timing Map



Observing this in pixel **timing inhomogeneity** for the **unIrradiated** sample and the presence of a tail at higher Lv1 values, we've decomposed the in pixel eft **for each Lv1**:

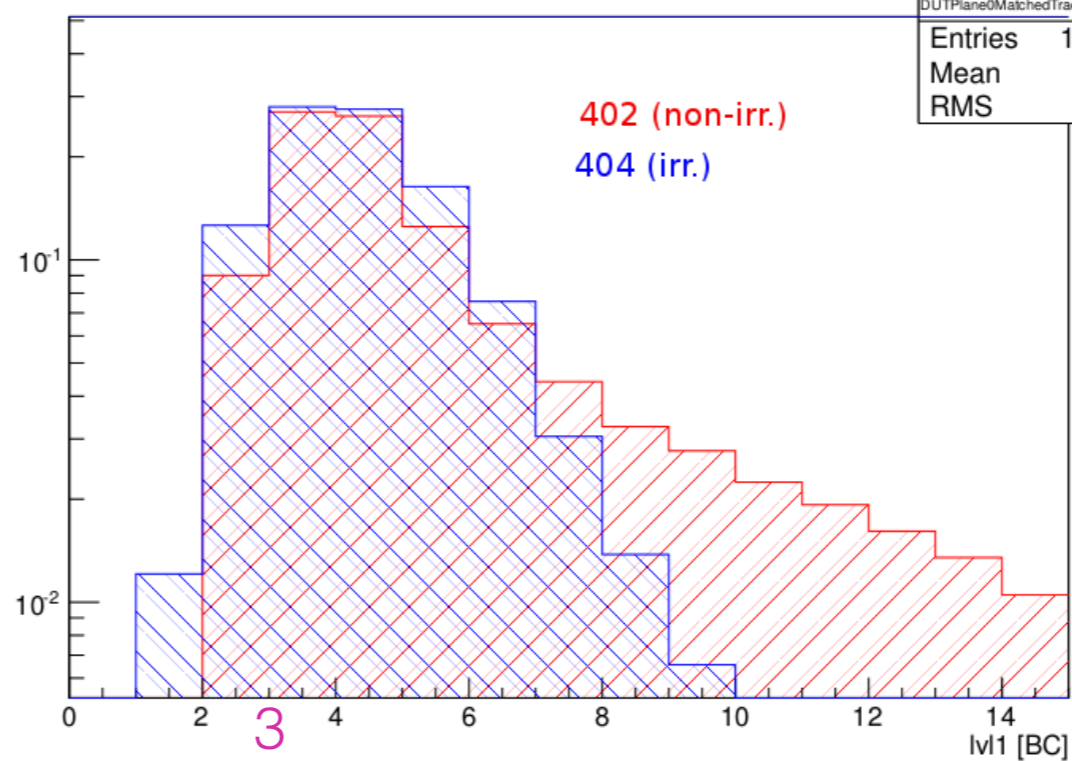
v4 InPixel Timing



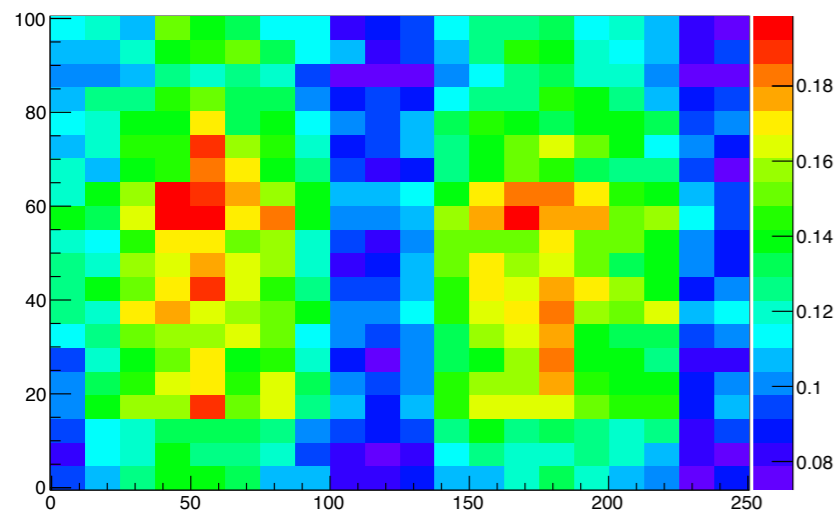
v4 InPixel Timing

$V_{th}=0.84$ V $V_{bias}=5$ V

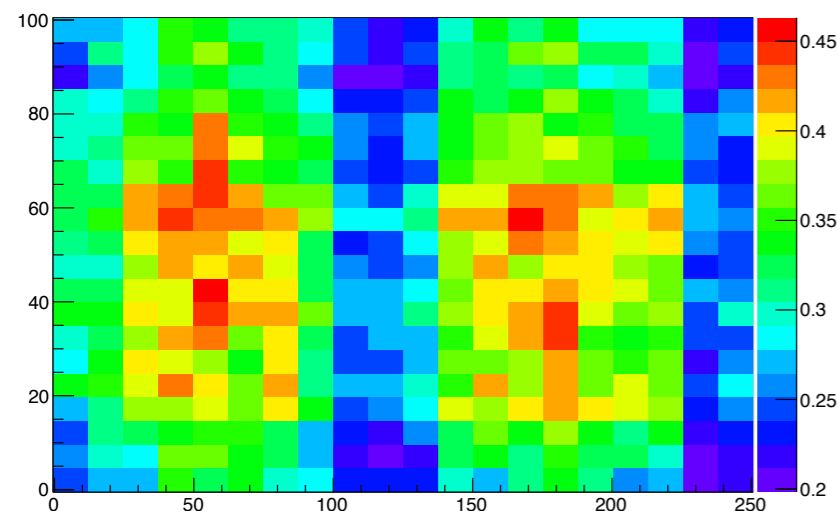
DUTPlane0MatchedTracksPositionYC	
Entries	138226
Mean	4.83
RMS	2.62



DUT Plane0 In Pixel Timing Map for $l=2$ bc



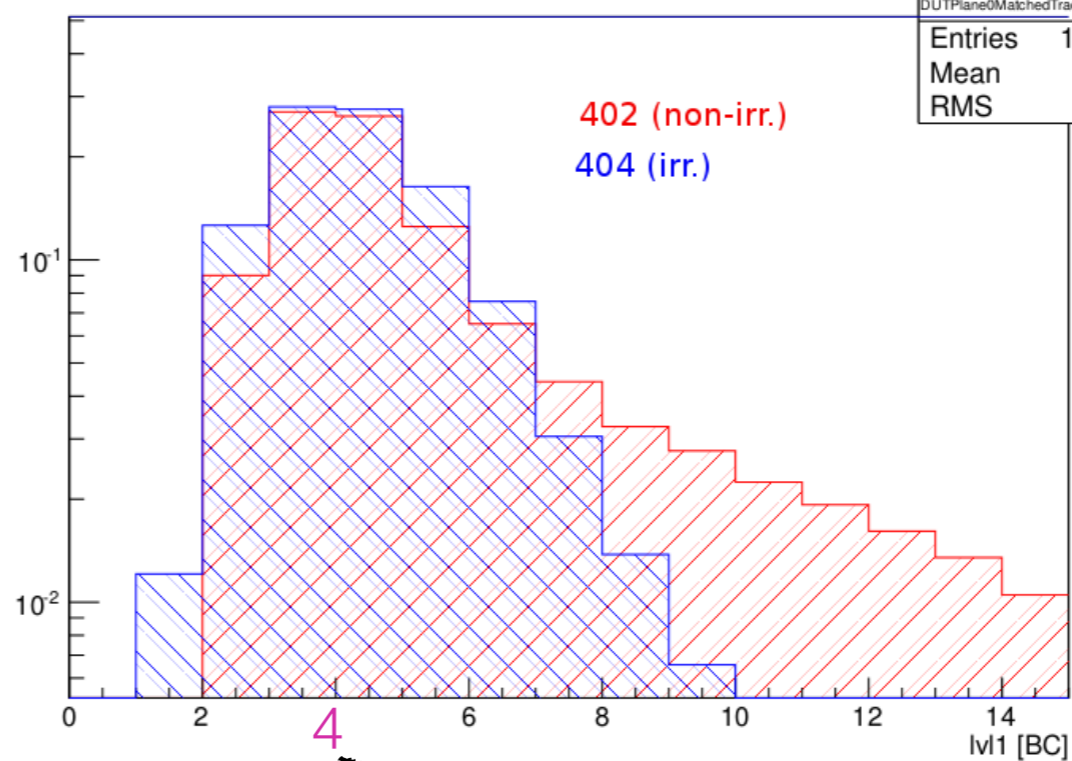
DUT Plane0 In Pixel Timing Map for $l=3$ bc



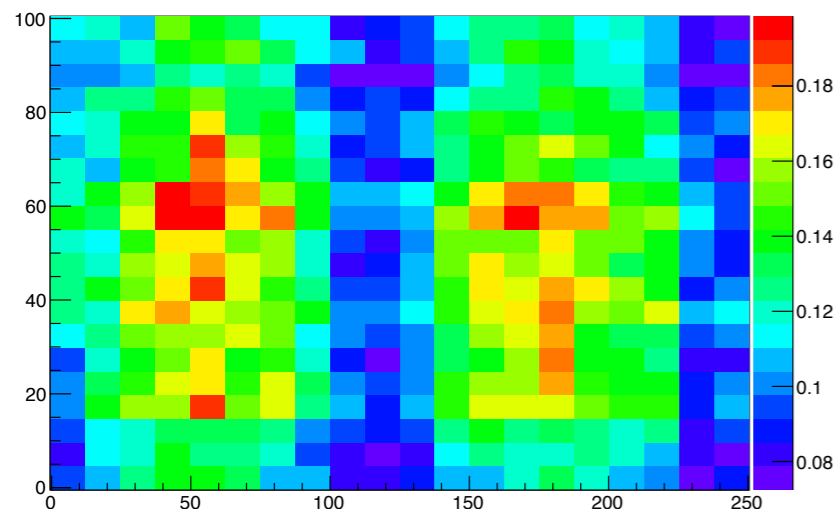
v4 InPixel Timing

$V_{th}=0.84$ V $V_{bias}=5$ V

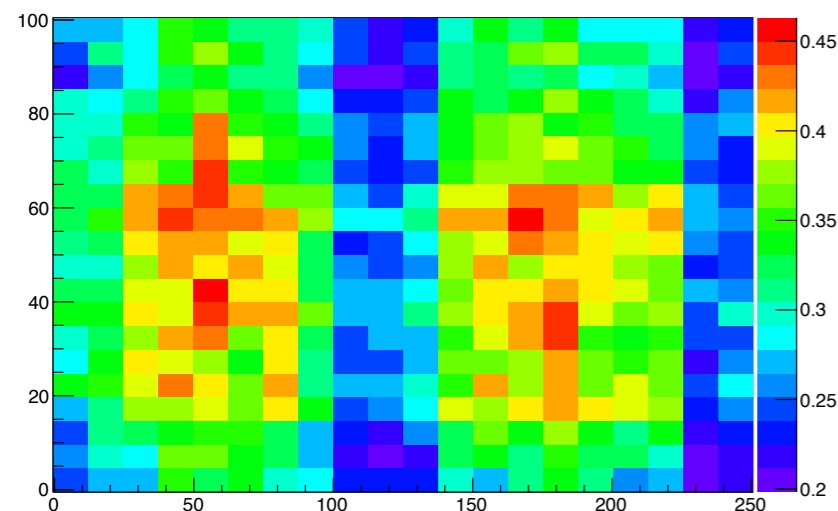
DUTPlane0MatchedTracksPositionYC	
Entries	138226
Mean	4.83
RMS	2.62



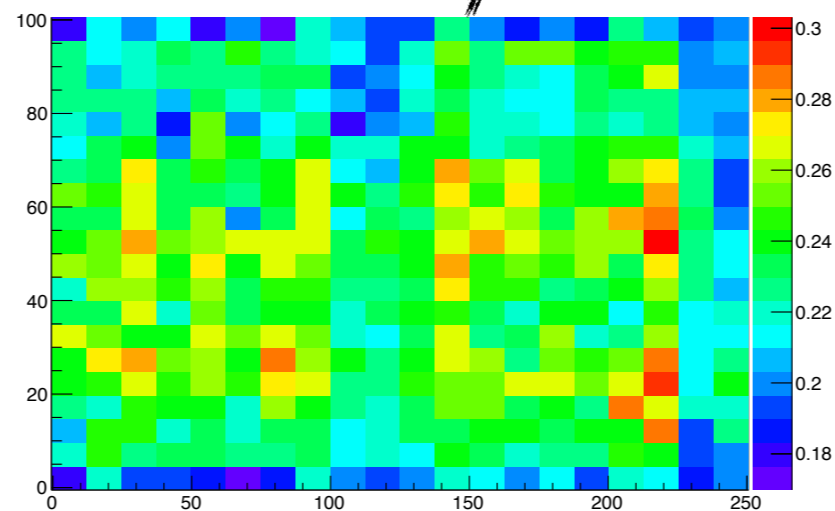
DUT Plane0 In Pixel Timing Map for lM= 2 bc



DUT Plane0 In Pixel Timing Map for lM= 3 bc

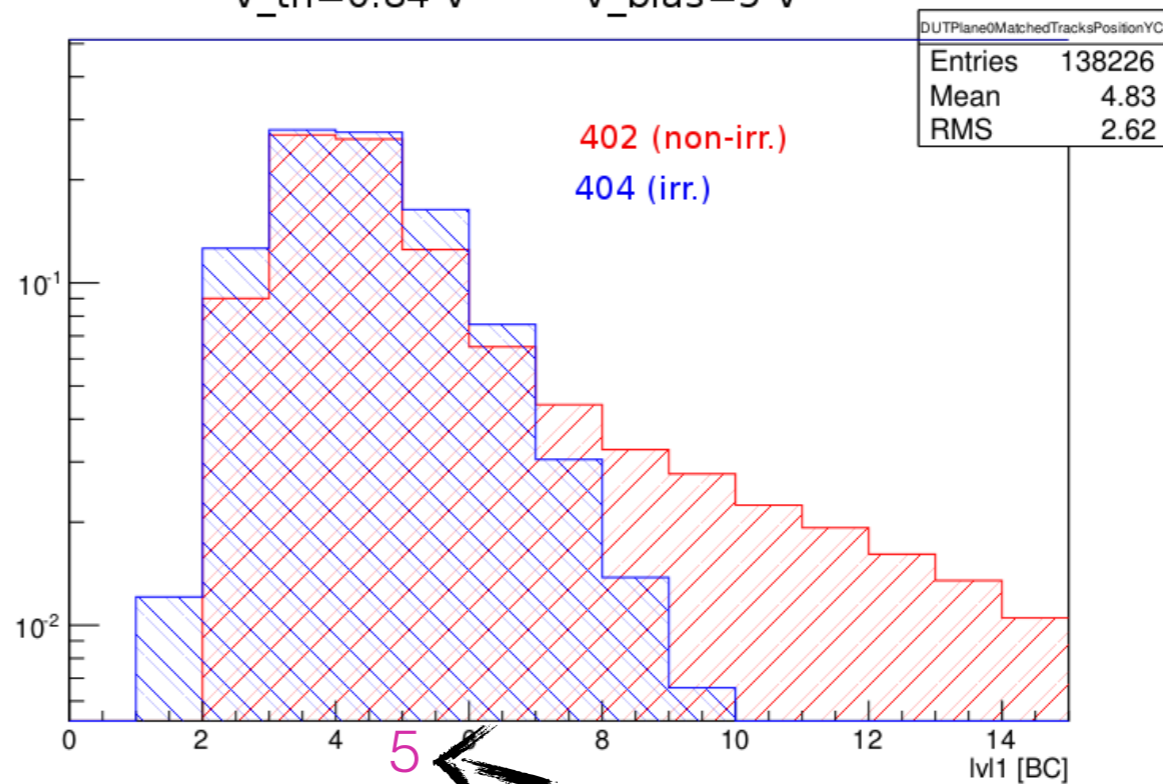


DUT Plane0 In Pixel Timing Map for lM= 4 bc

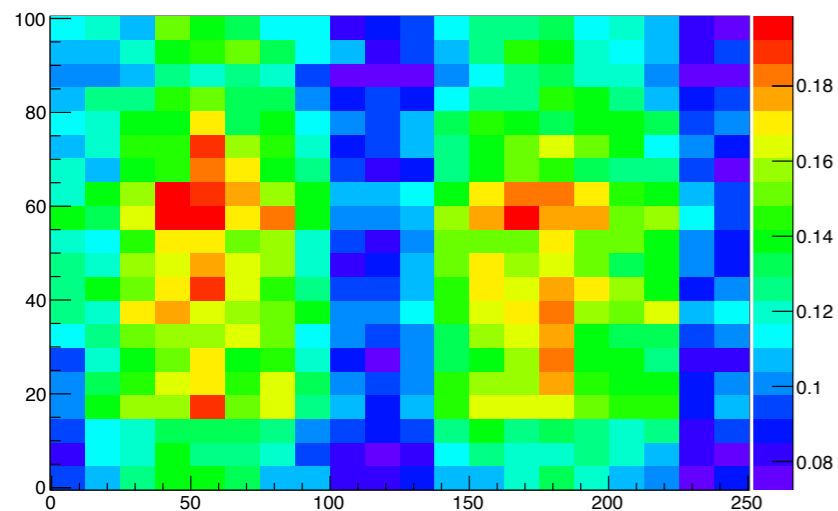


v4 InPixel Timing

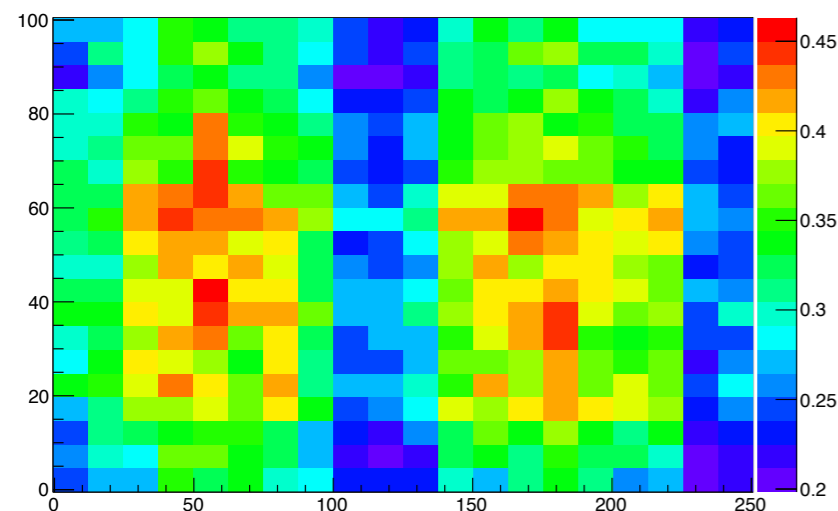
$V_{th}=0.84$ V $V_{bias}=5$ V



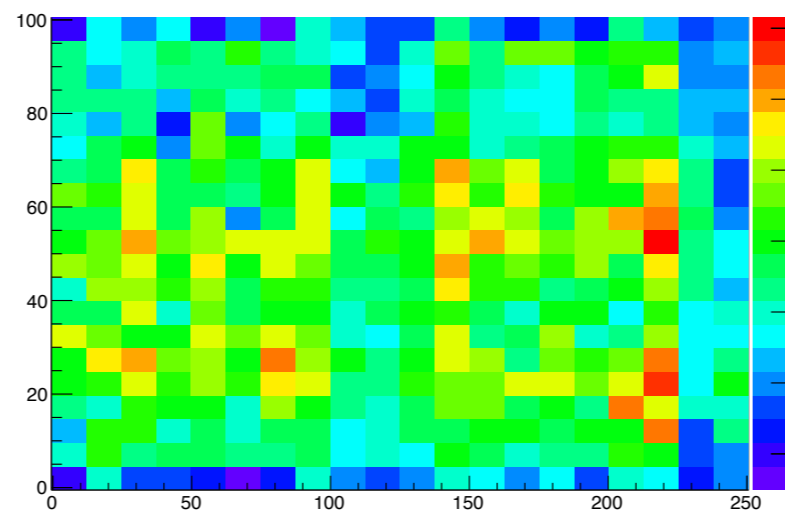
DUT Plane0 In Pixel Timing Map for lvl= 2 bc



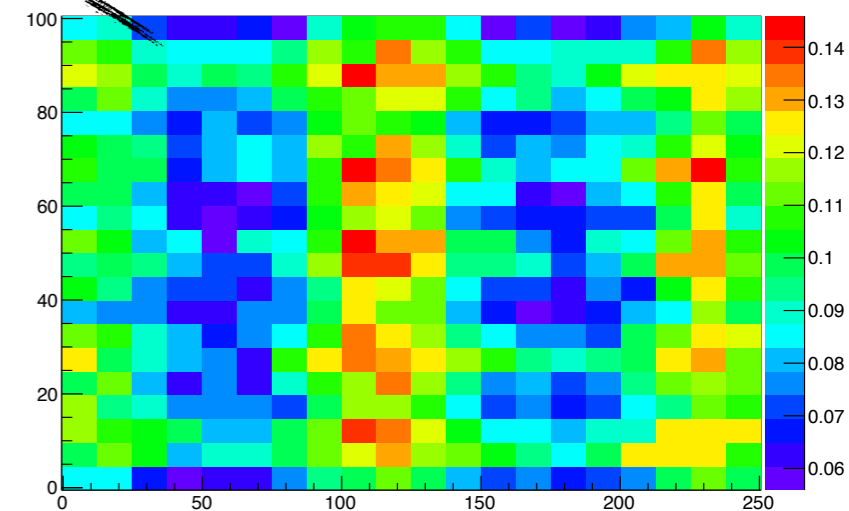
DUT Plane0 In Pixel Timing Map for lvl= 3 bc



DUT Plane0 In Pixel Timing Map for lvl= 4 bc

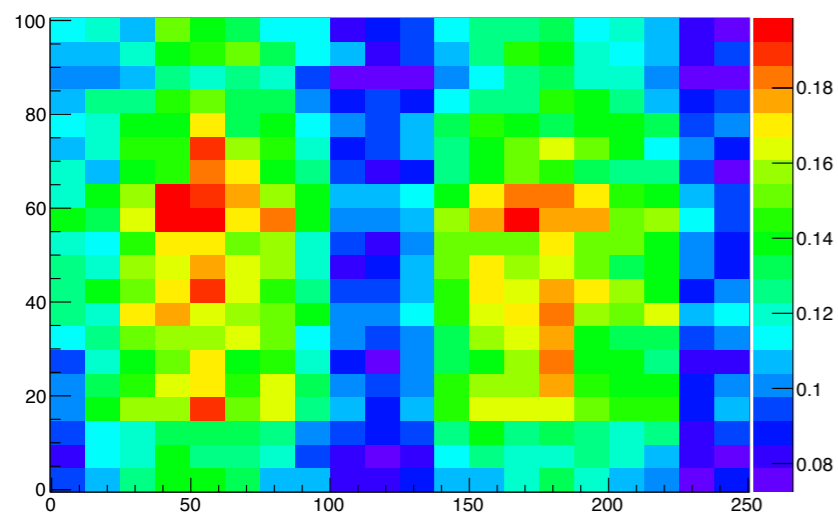


DUT Plane0 In Pixel Timing Map for lvl= 5 bc



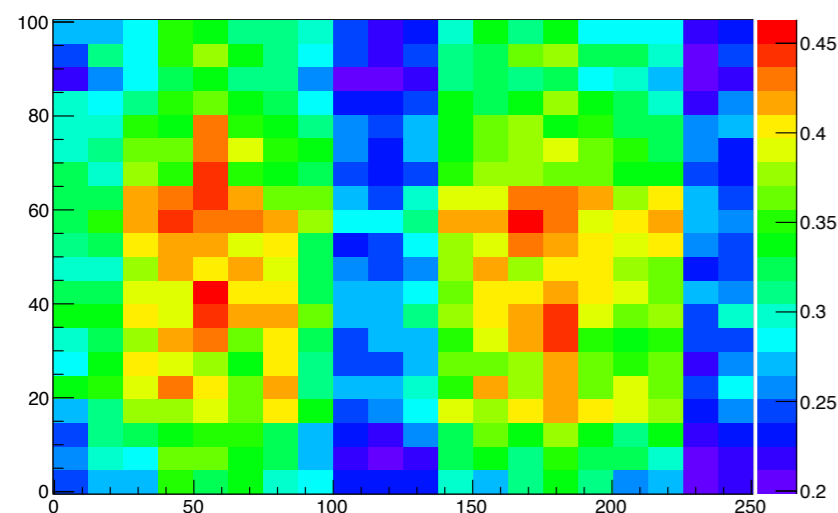
v4 InPixel Timing

DUT Plane0 In Pixel Timing Map for $lvl= 2$ bc

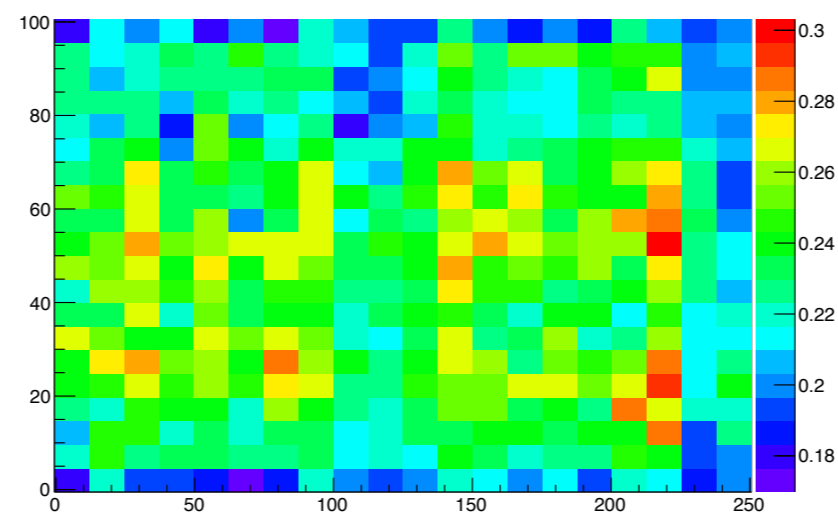


Contribution from the pixel edges for the non-irradiated sample. Consistent with diffusion effects.

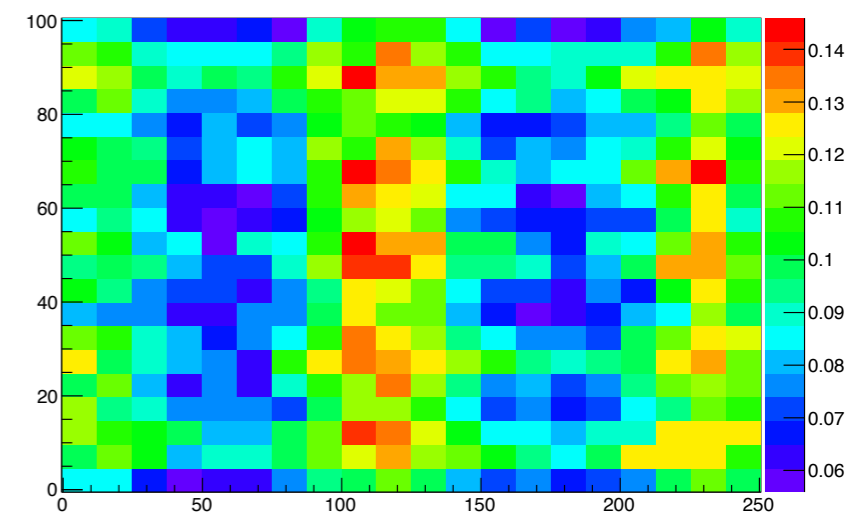
DUT Plane0 In Pixel Timing Map for $lvl= 3$ bc



DUT Plane0 In Pixel Timing Map for $lvl= 4$ bc



DUT Plane0 In Pixel Timing Map for $lvl= 5$ bc

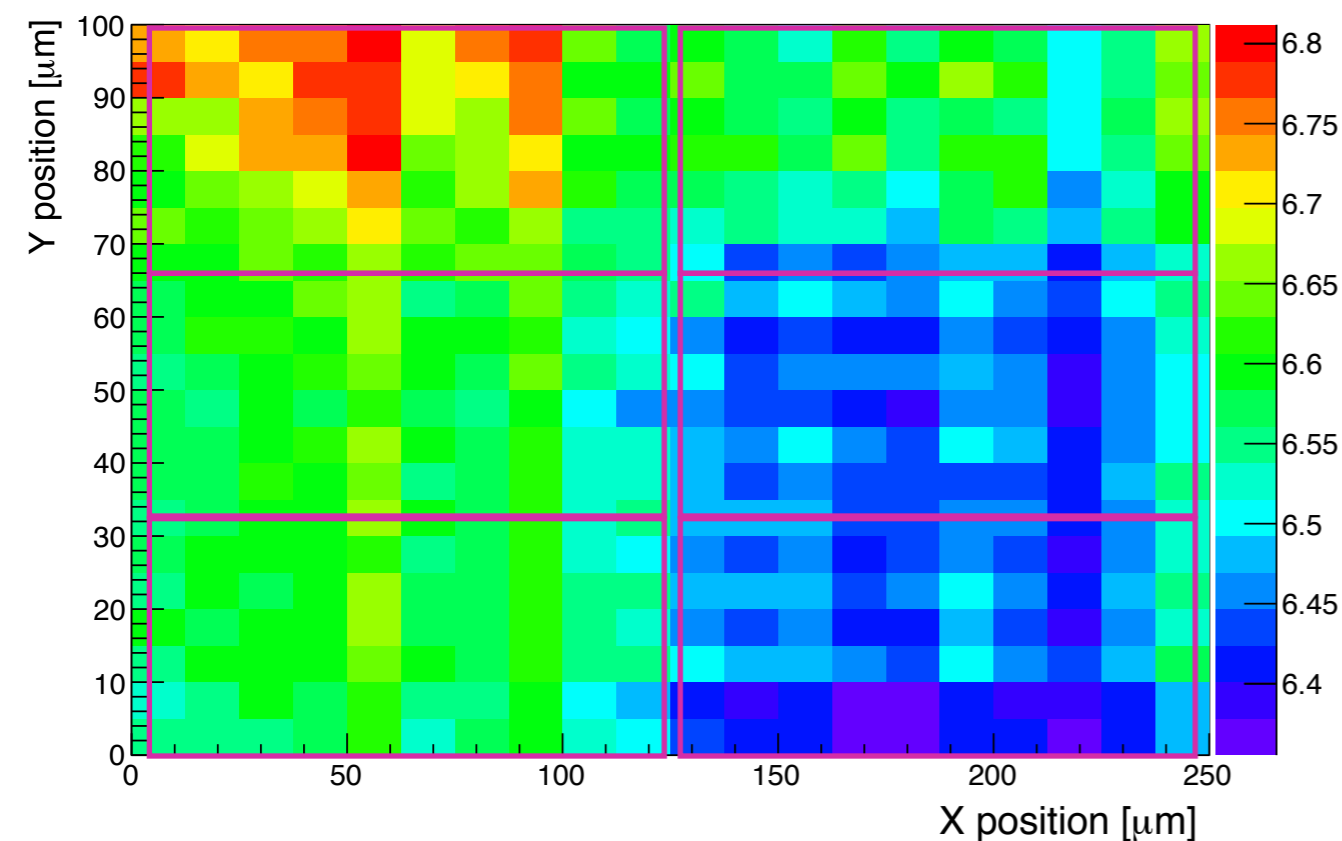


v4 ToT inPixel

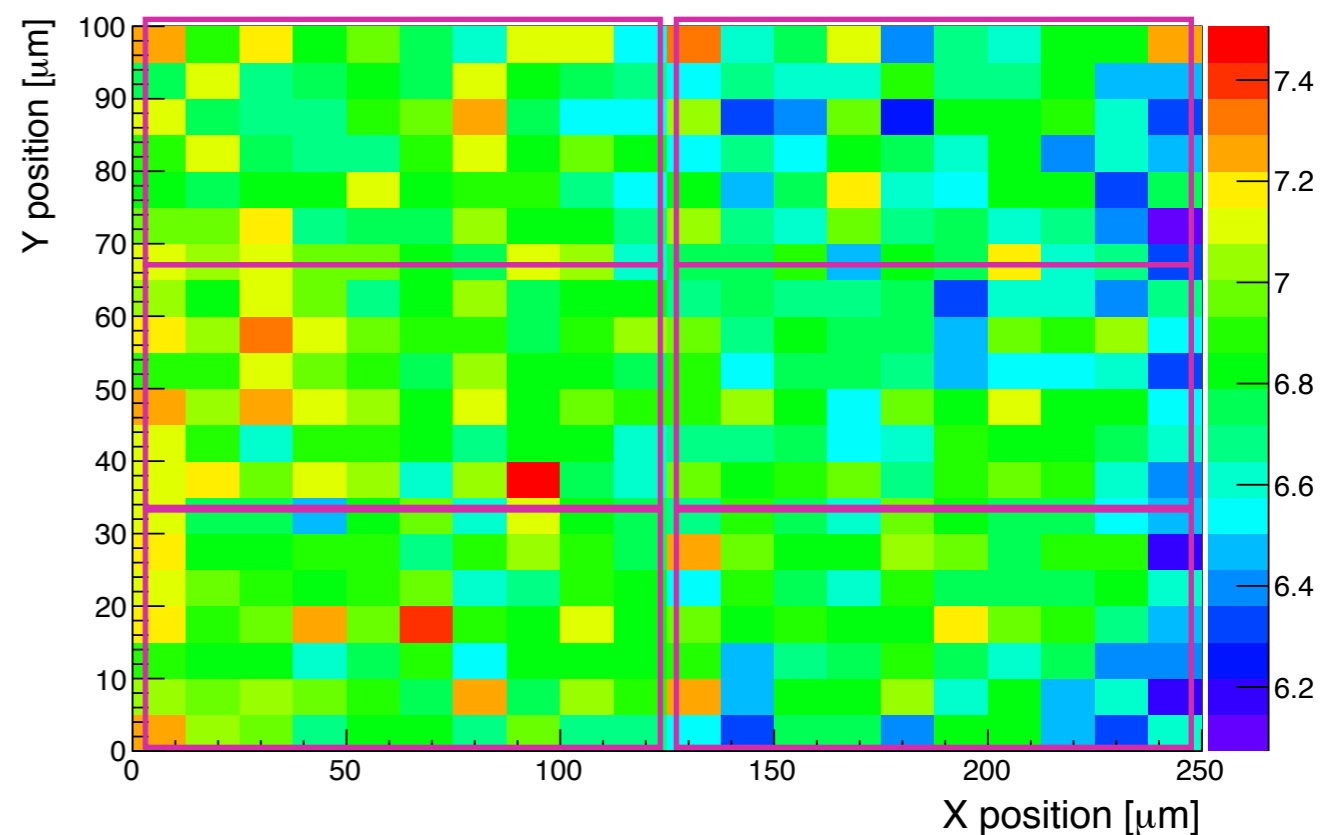
402, unIrradiated
Bias 12 V, Th 0.84 V
Run: 3911 - 3915

404, $10^{15} n_{eq}/cm^2$
Bias 30 V, Th 0.84V
Run: 4074

DUT Plane0 In Pixel ToT Map



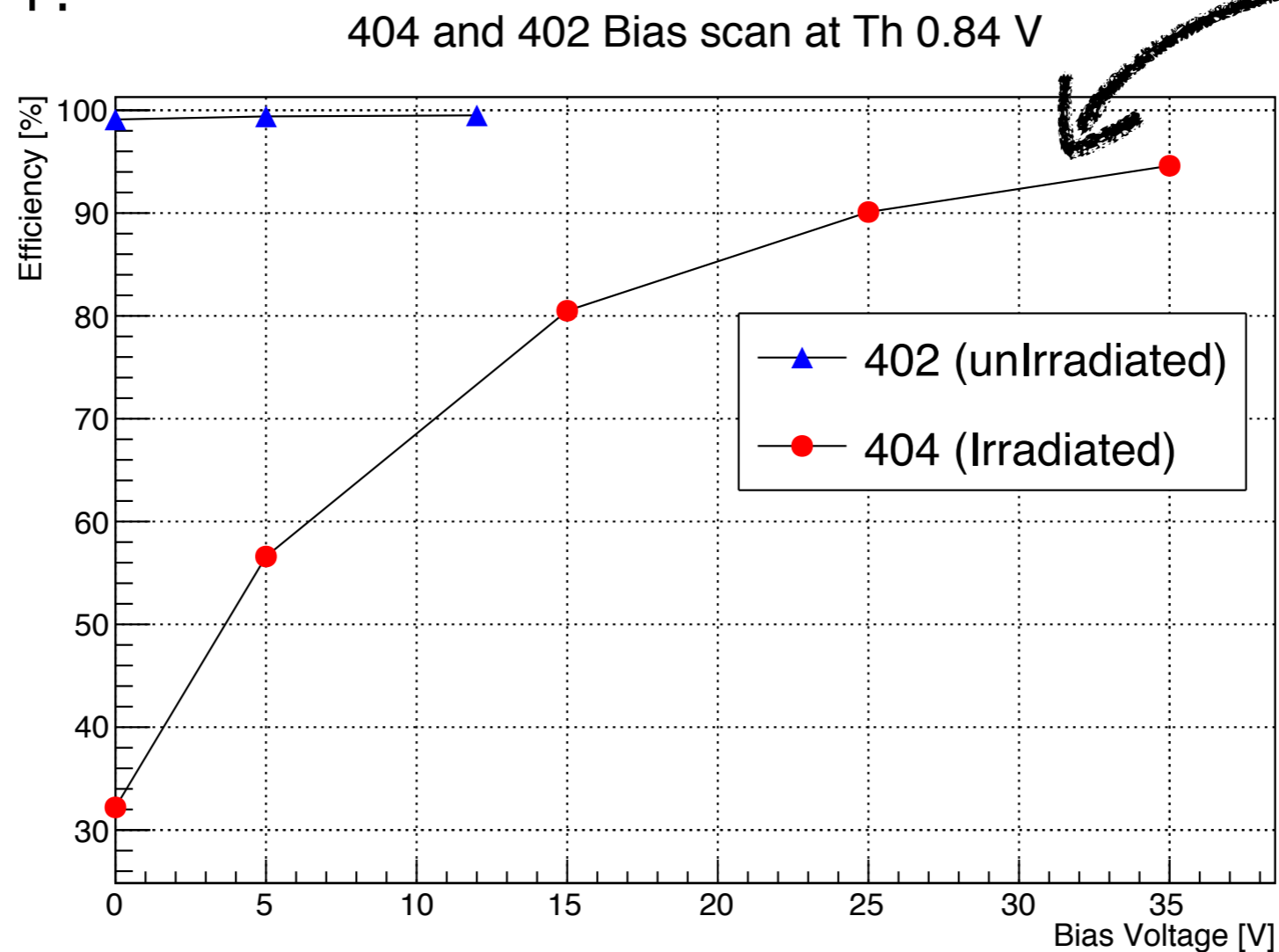
DUT Plane0 In Pixel ToT Map



InPixel ToT inhomogeneities, under investigation with the unit-cell design

Bias Scan

eff. for all Lv1:



Need to reach the plateau ?

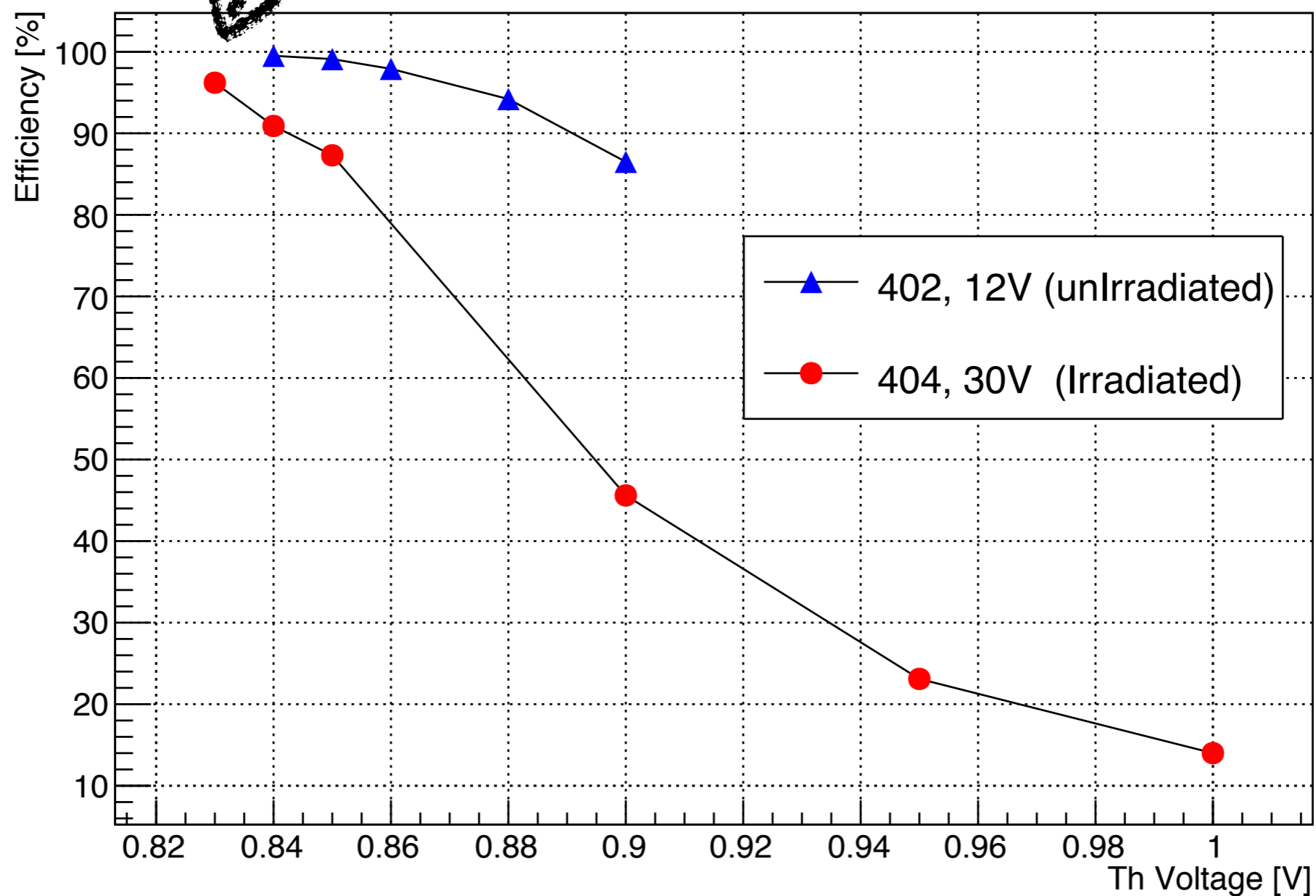
- Need to reach **higher depletion** voltages. Limited availability of prototypes during data taking.
- Full range will be scanned with source measurements on new samples.

Threshold Scan

eff. for all Lv1:

Tuning / Operation limit

404 and 402 Threshold scan

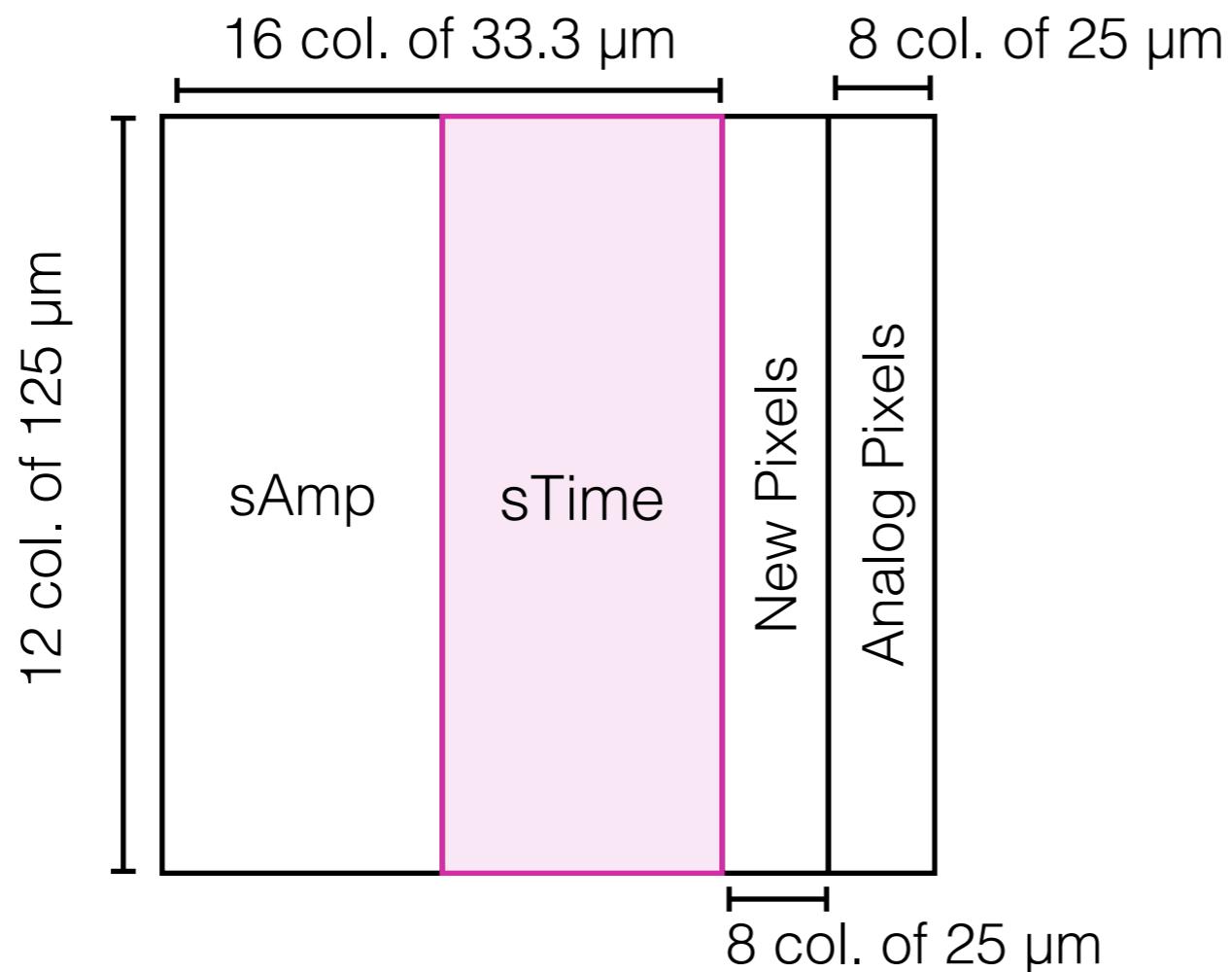


Conclusions

- Efficiency before irradiation >99%
- Decrease of efficiency to 96% at $10^{15} n_{eq}/cm^2$, irradiated samples efficiency can be increased with higher depletion voltages.
- Diffusion component seen for the unirradiated sample.
- Timing dependence on Threshold tuning indicates some time walk
- This time features will be addressed in next AMS prototypes.

v4 structure

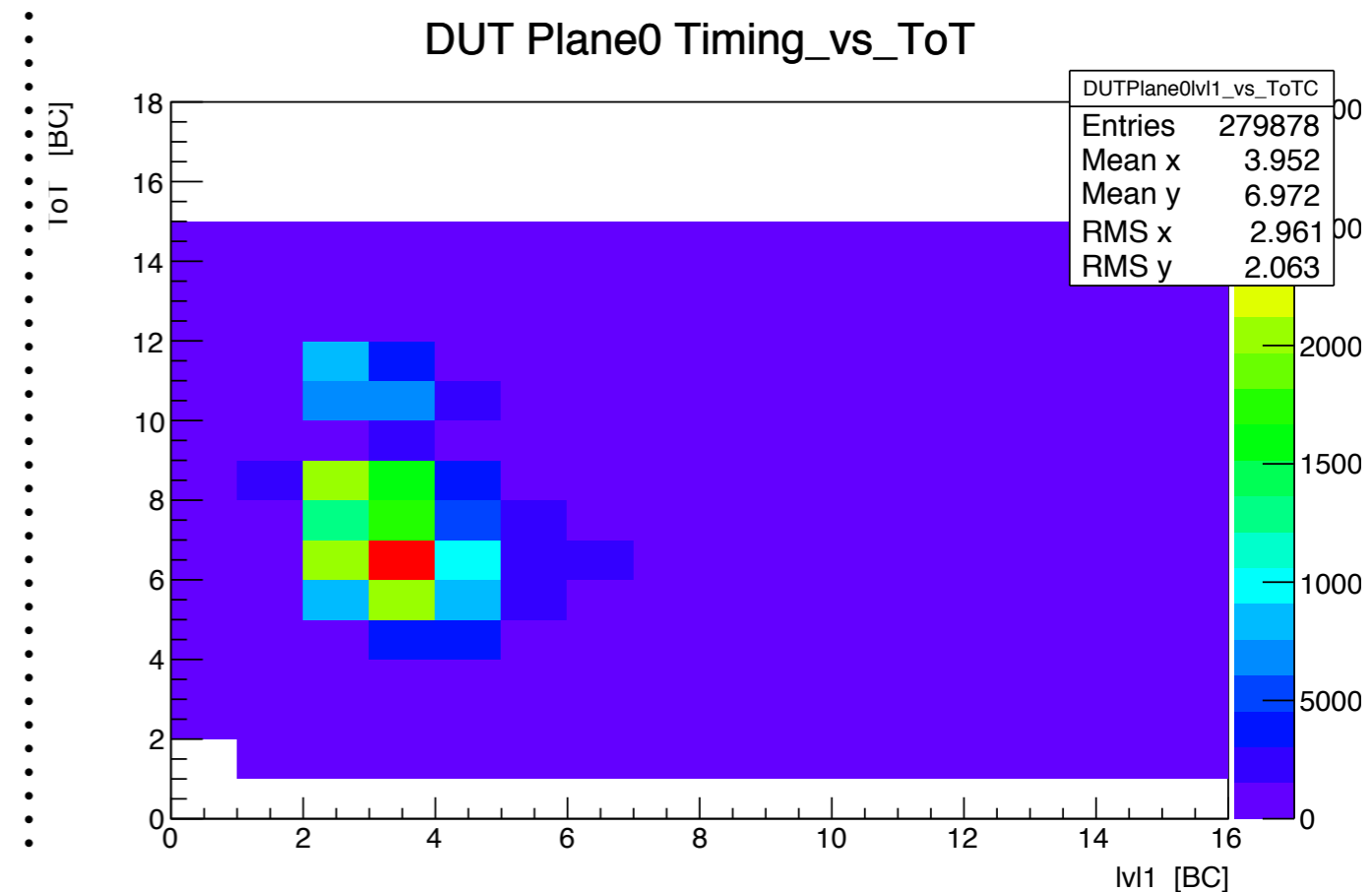
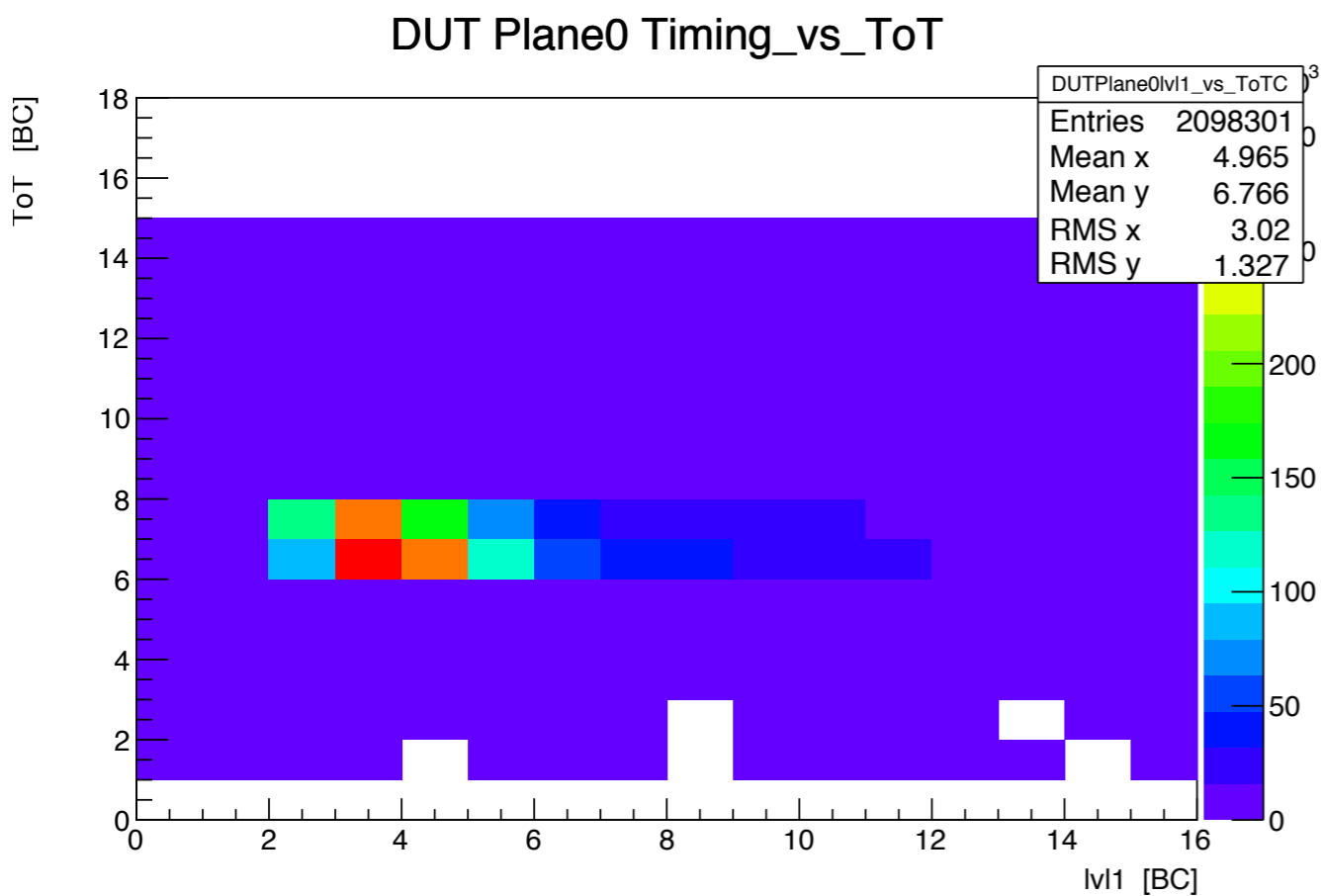
- Several HVCMOS pixels flavours



v4 ToT vs Lv1

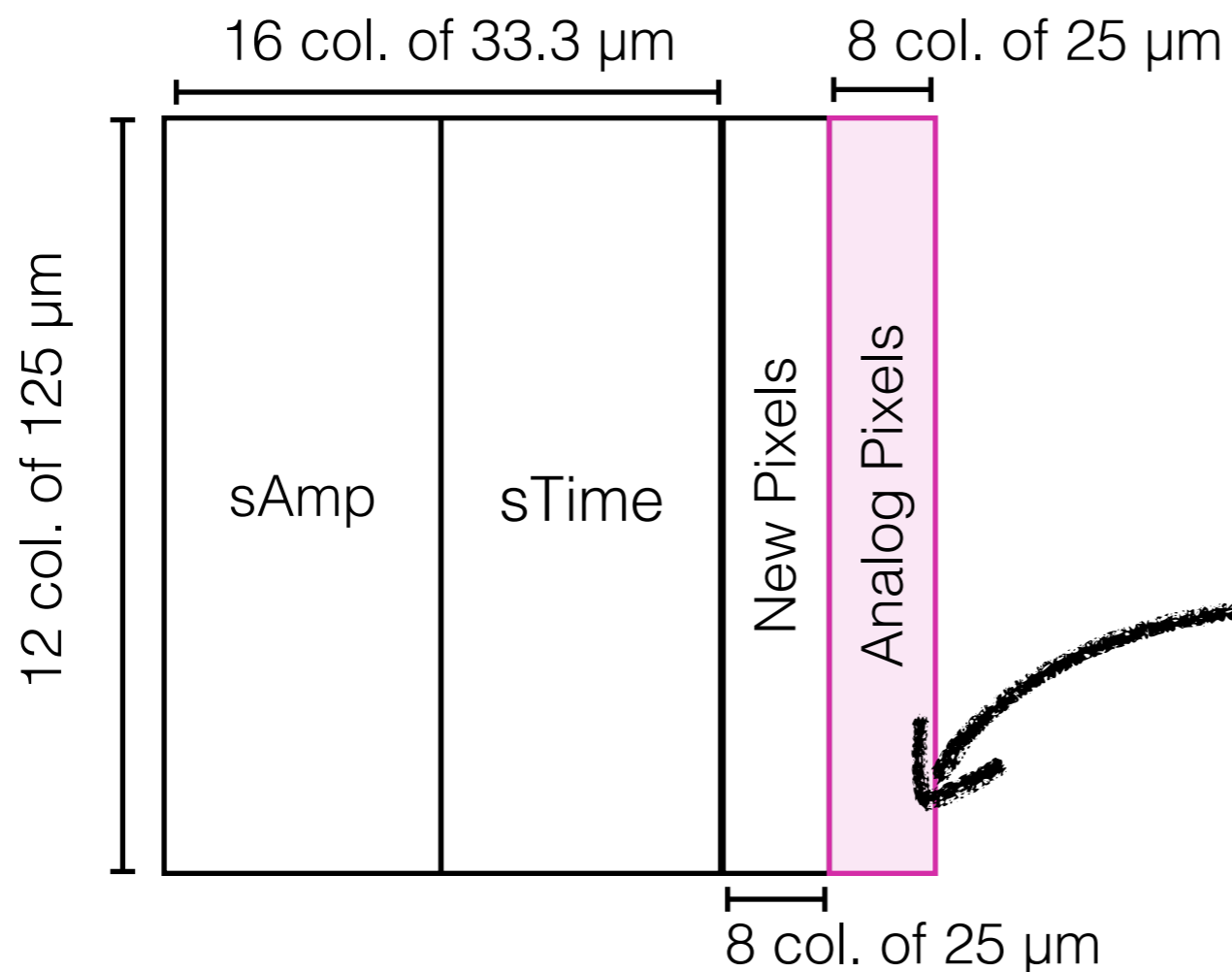
402, unIrradiated
Bias 12 V, Th 0.84 V
Run: 3911 - 3915

404, 10^{15} n_{eq}/cm²
Bias 30 V, Th 0.84V
Run: 4074



v4 structure

- Several HVCMOS pixels flavours



Output amplitude
dependent on input signal

Analog pixel - ToT vs Lv1

402, unIrradiated
Bias 12 V, Th 0.84 V
Run: 3966 - 3967

DUT Plane0 Timing_vs_ToT

